

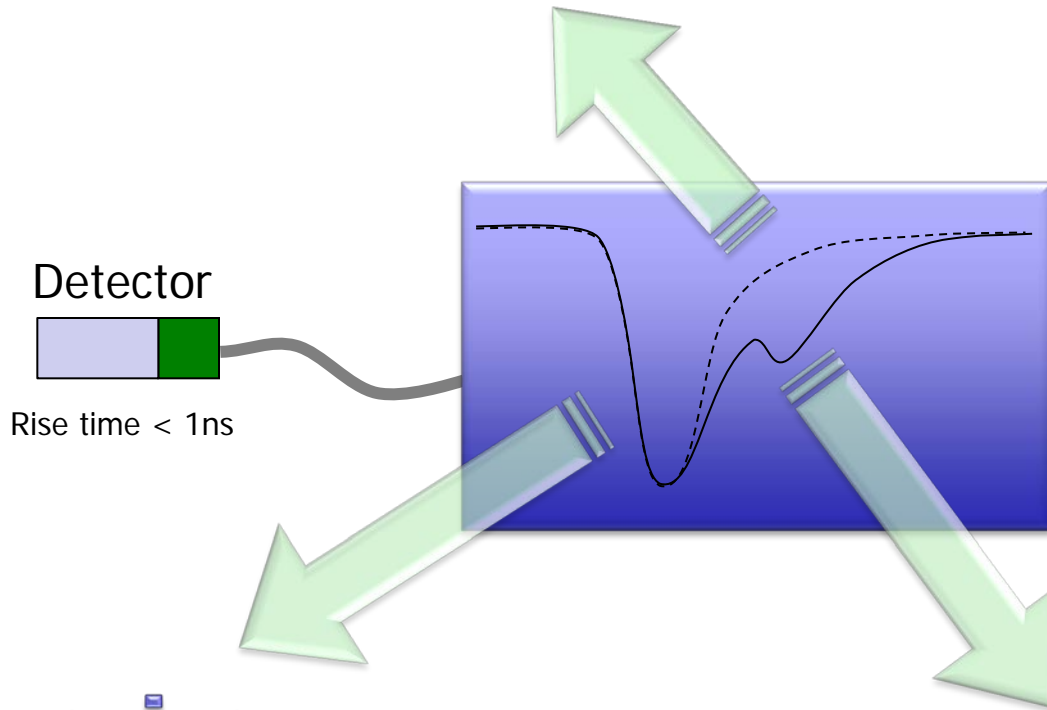


**Paul Scherrer Institute**

Stefan Ritt

**Applications and future of Switched Capacitor Arrays (SCA)  
for ultrafast waveform digitizing**

## Pulse shape discrimination

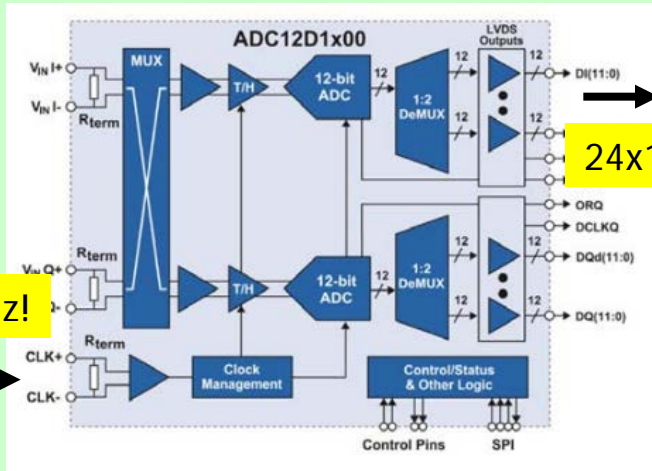


**Ultra-precise  
timing < 10ps**

**Pile-up  
recognition**

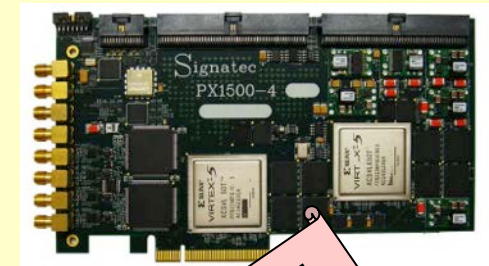
# Can it be done with FADCs?

- 8 bits – 3 GS/s – 1.9 W → 24 Gbits/s
- 10 bits – 3 GS/s – 3.6 W → 30 Gbits/s
- 12 bits – 3.6 GS/s – 3.9 W → 43.2 Gbits/s
- 14 bits – 0.4 GS/s – 2.5 W → 5.6 Gbits/s



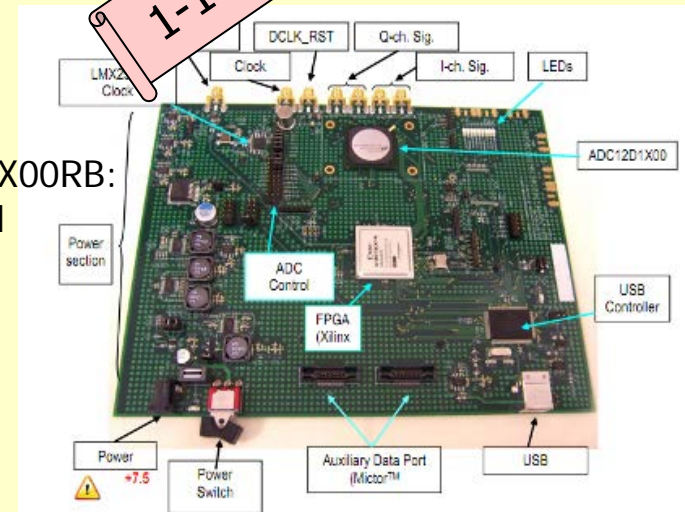
- Requires high-end FPGA
- Complex board design
- FPGA power

PX1500-4:  
2 Channel  
3 GS/s  
8 bits

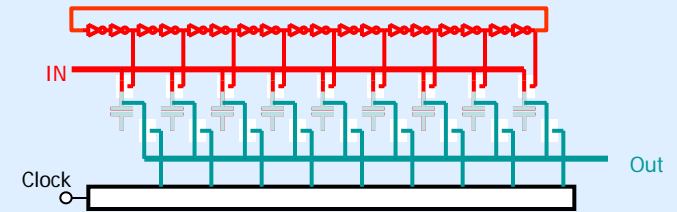


1-10 k€ / channel

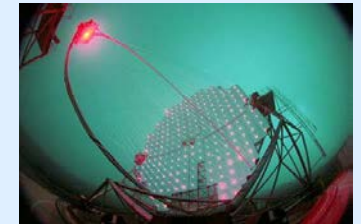
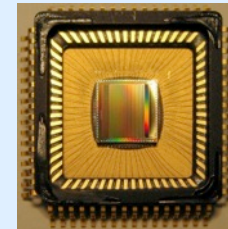
ADC12D1X00RB:  
1 Channel  
1.8 GS/s  
12 bits



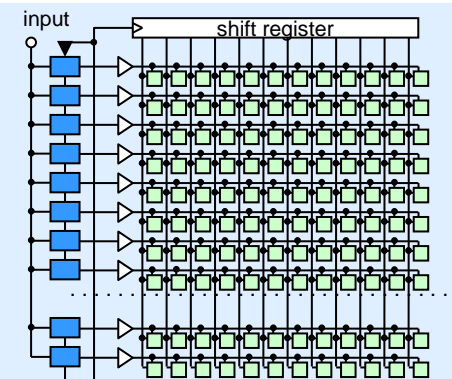
- Design Principles and Limitations of Switched Capacitor Arrays (SCA)



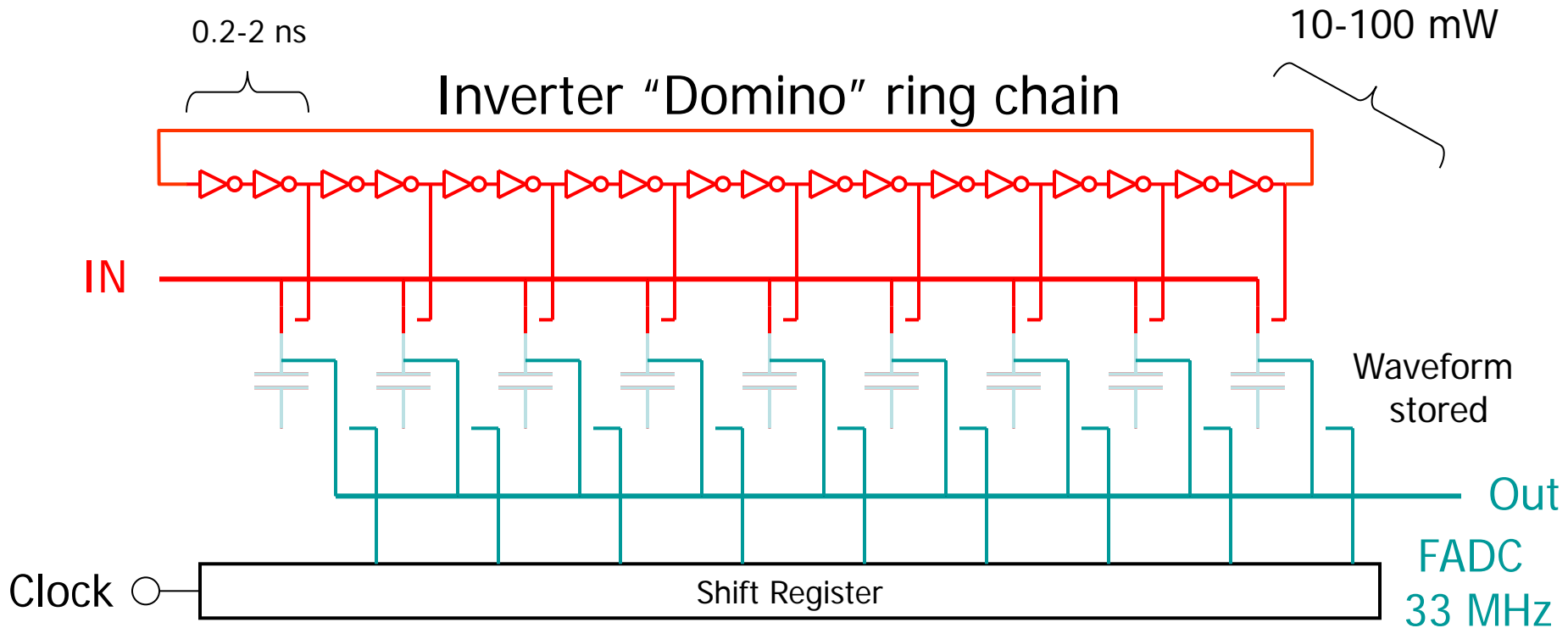
- Overview of Chips and Applications



- Future Design Directions

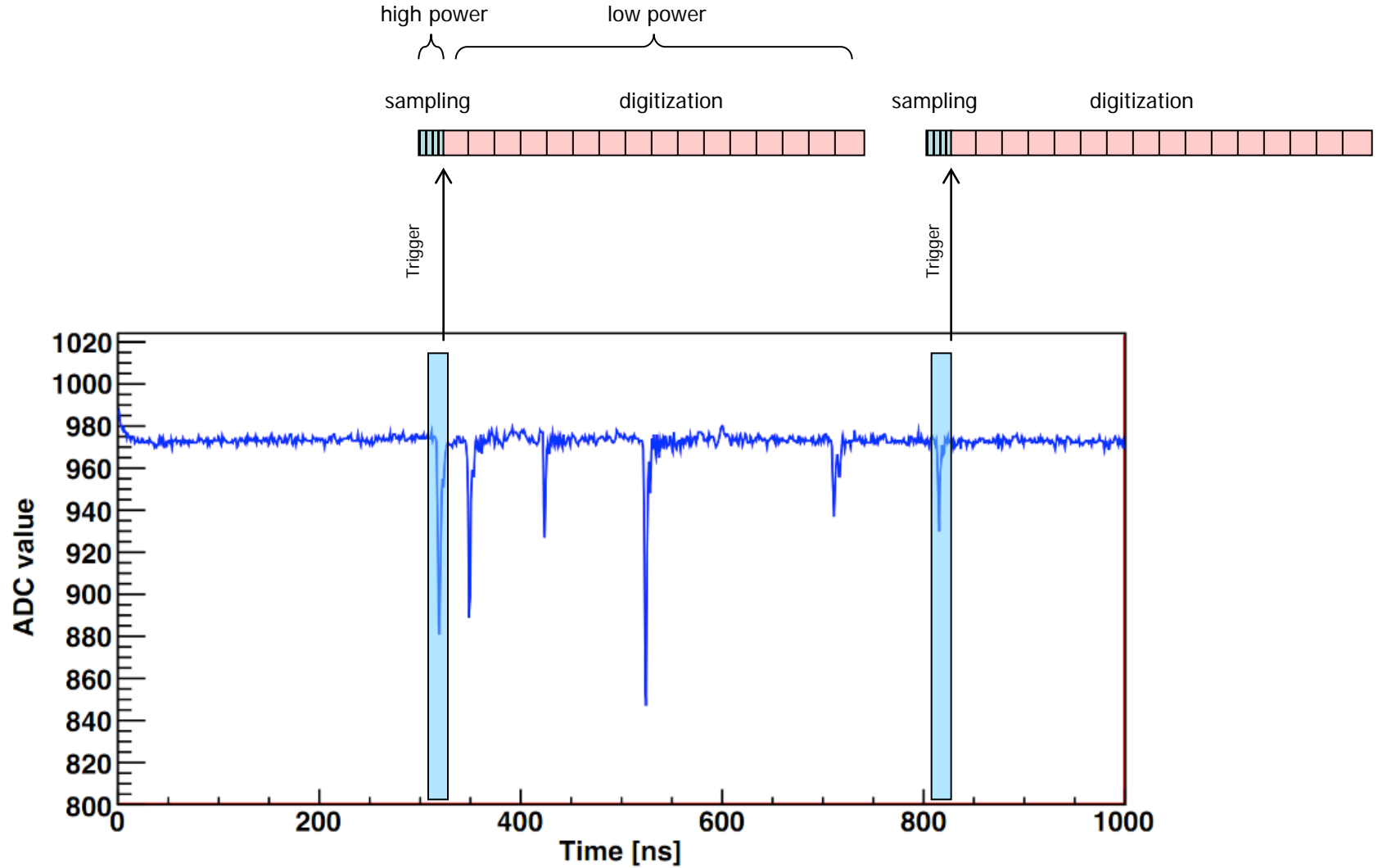


# Switched Capacitor Array (Analog Memory)

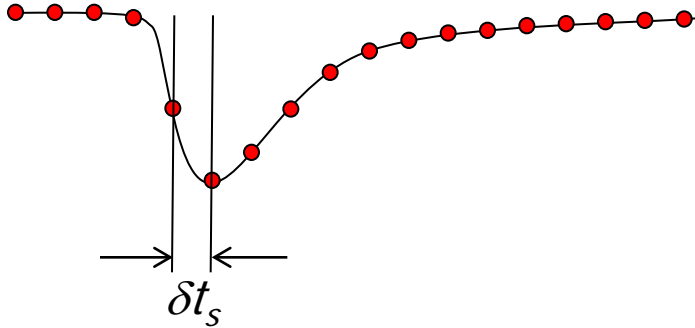


"Time stretcher" GHz  $\rightarrow$  MHz

# Digitizing only short time windows



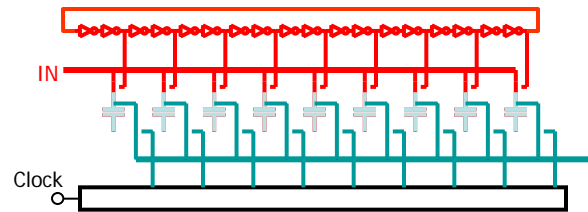
# Time Stretch Ratio (TSR)



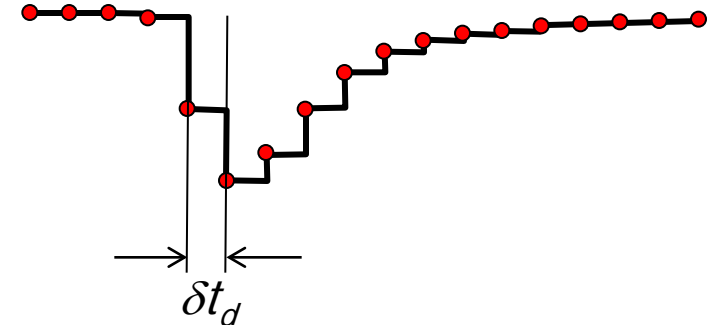
$$TSR \equiv \frac{\delta t_s}{\delta t_d}$$

Typical values:

- $\delta t_s = 0.5 \text{ ns}$  (2 GSPS)
- $\delta t_d = 30 \text{ ns}$  (33 MHz)
- $TSR = 60$

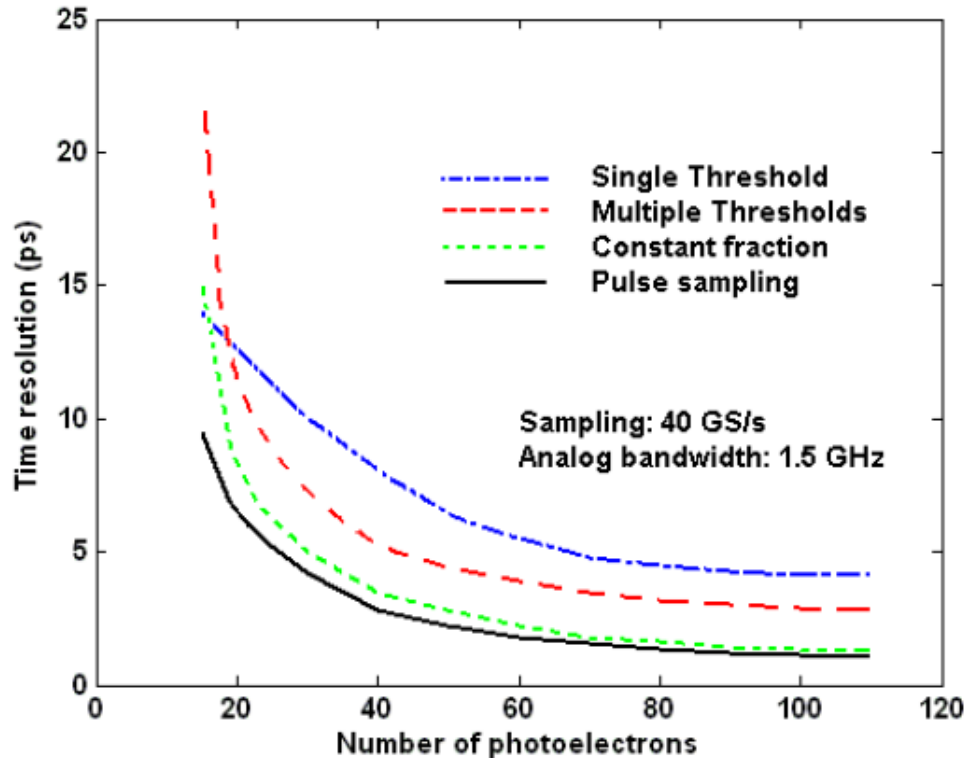


Dead time =  
Sampling Window  $\cdot$   $TSR$   
  
(e.g.  $100 \text{ ns} \cdot 60 = 6 \mu\text{s}$ )



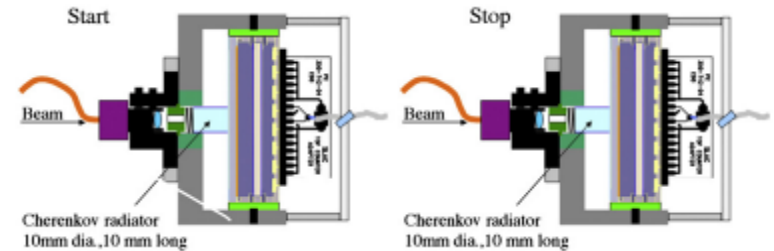
# How to measure best timing?

Simulation of MCP with realistic noise and different discriminators



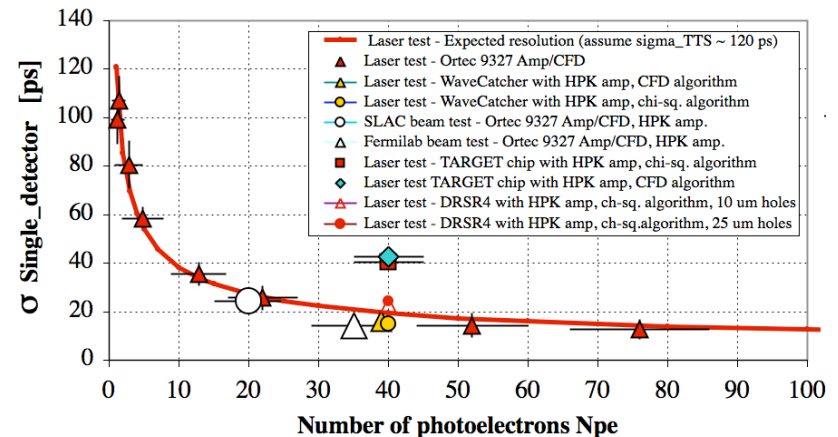
J.-F. Genat et al., arXiv:0810.5590 (2008)

Beam measurement at SLAC & Fermilab



'Pixilated' TOF

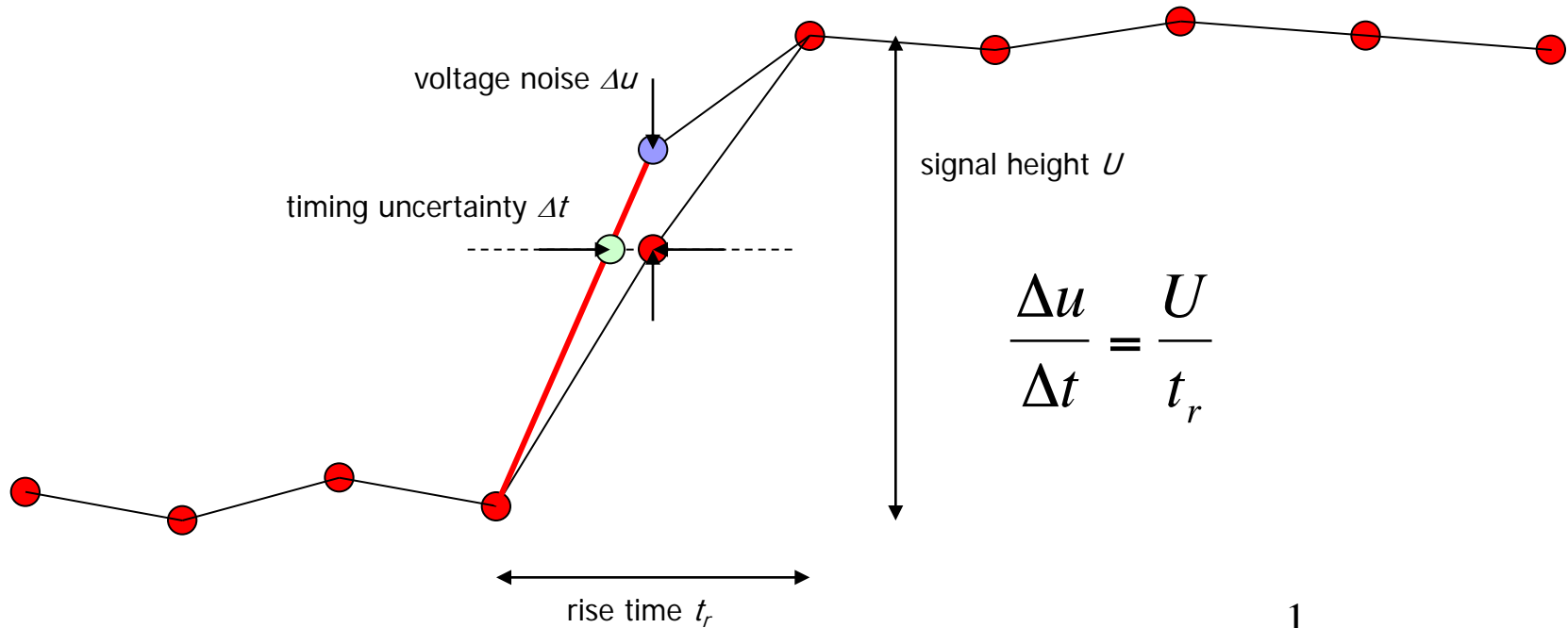
J.V., 11.4.2011



D. Breton et al., NIM A629, 123 (2011)



# How is timing resolution affected?



$$\Delta t = \frac{\Delta u}{U} \cdot t_r = \frac{\Delta u}{U \sqrt{n}} \cdot t_r = \frac{\Delta u}{U} \cdot \frac{t_r}{\sqrt{t_r \cdot f_s}} = \frac{\Delta u}{U} \cdot \frac{\sqrt{t_r}}{\sqrt{f_s}} = \frac{\Delta u}{U} \cdot \frac{1}{\sqrt{3 f_s \cdot f_{3dB}}}$$

$t_r \approx \frac{1}{3 f_{3dB}}$

number of samples on slope

**Simplified estimation!**

# How is timing resolution affected?

$$\Delta t = \frac{\Delta u}{U} \cdot \frac{1}{\sqrt{3 f_s \cdot f_{3dB}}}$$

Assumes zero aperture jitter

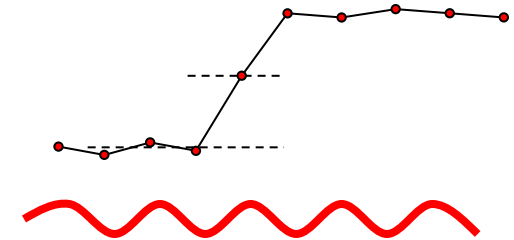


	$U$	$\Delta u$	$f_s$	$f_{3dB}$	$\Delta t$
today:	100 mV	1 mV	2 GSPS	300 MHz	~10 ps
optimized SNR:	1 V	1 mV	2 GSPS	300 MHz	1 ps
next generation:	100 mV	1 mV	10 GSPS	3 GHz	1 ps

today:  
optimized SNR:  
next generation:



includes detector noise  
in the frequency region of the rise time  
and aperture jitter



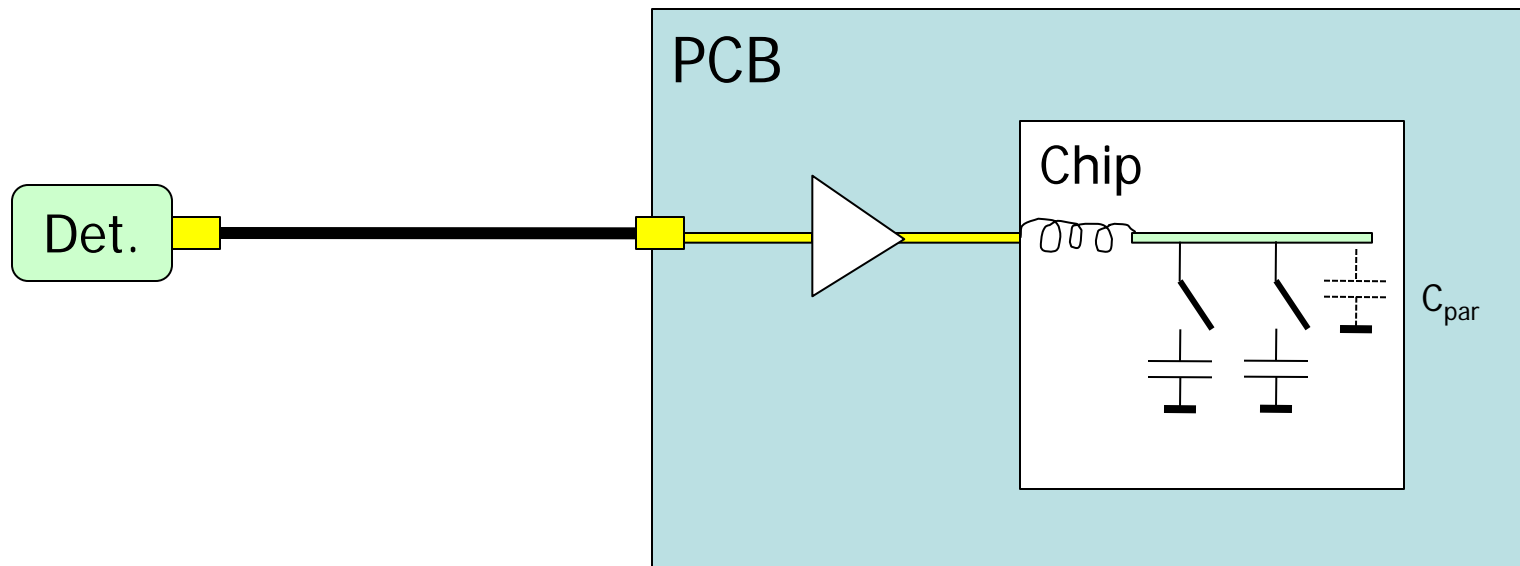
# Limits on analog bandwidth

- External sources
  - Detector
  - Cable
  - Connectors
  - PCB
  - Preamplifier

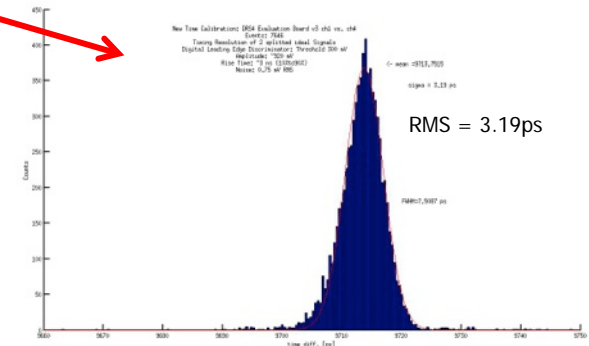
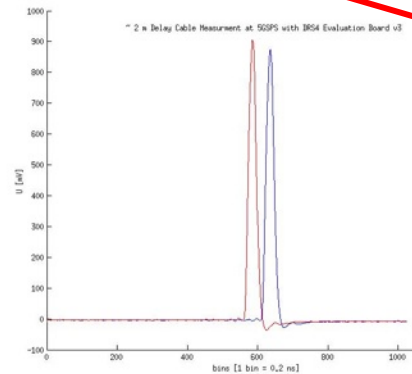
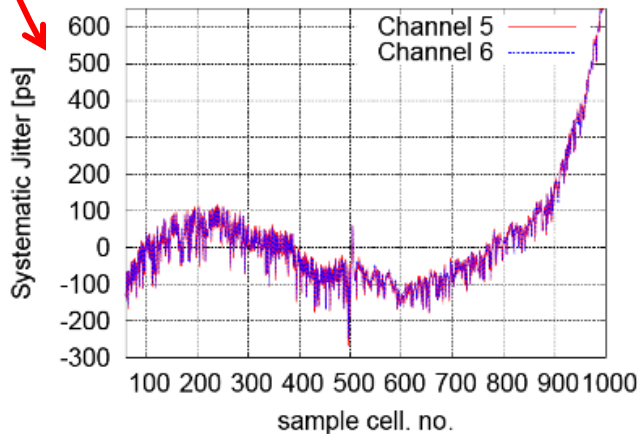
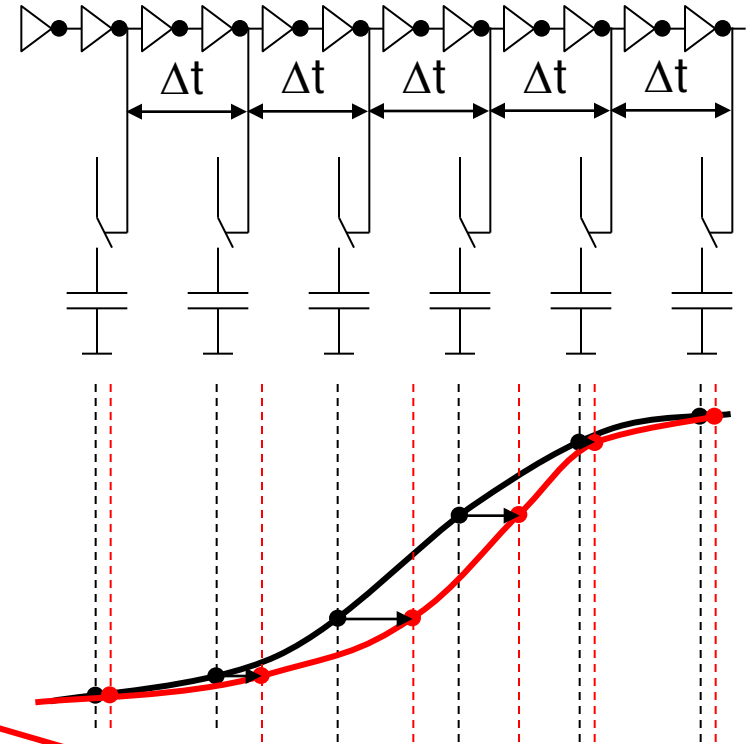
- Internal sources

- Bond wire
  - Input bus
  - Write switch
  - Storage cap
- Low pass filter
- Low pass filter

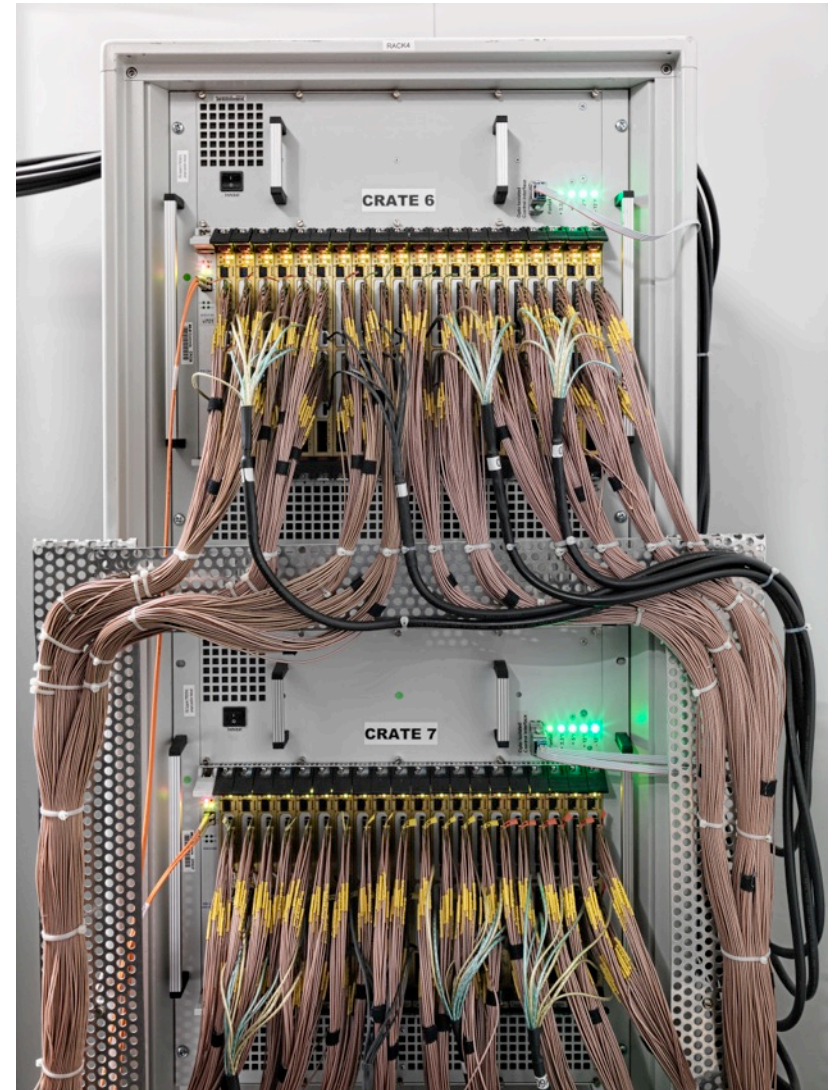
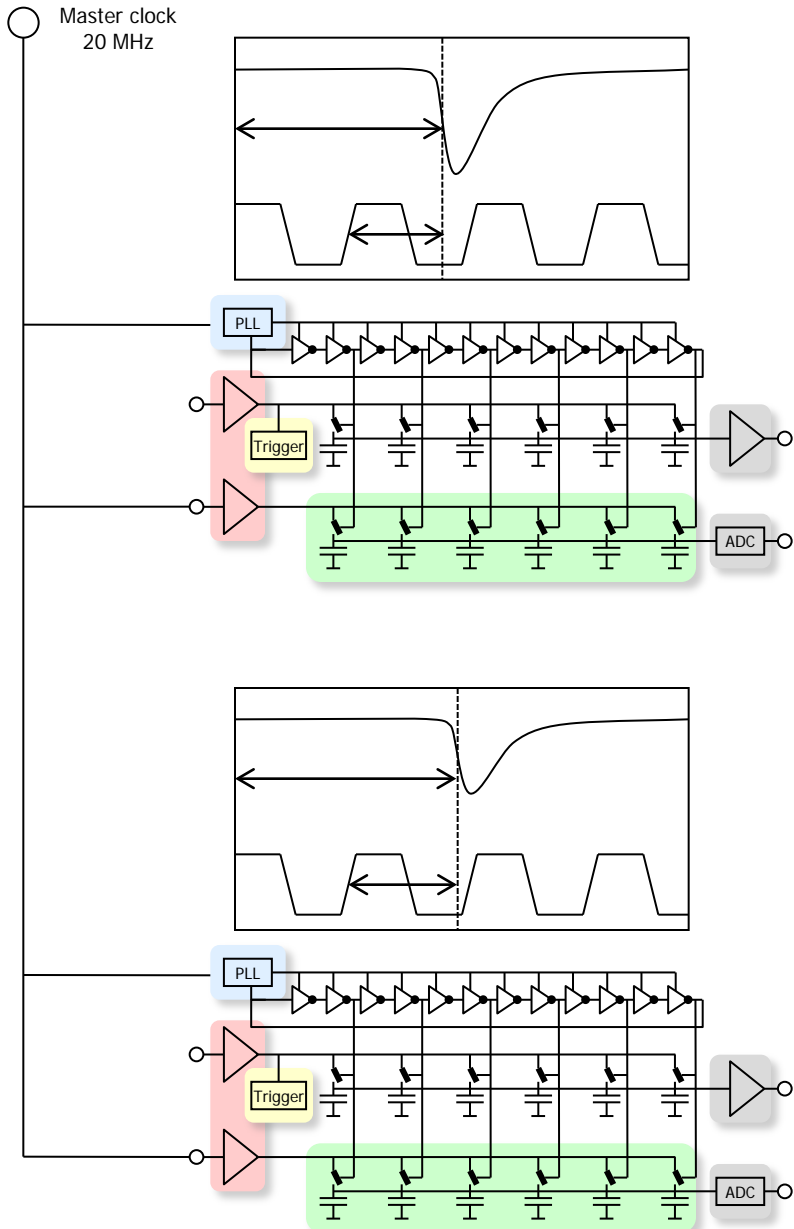
$$f_{3db} = \frac{1}{2\pi RC}$$



- Bin-to-bin variation:  
"differential timing nonlinearity"
- Difference along the whole chip:  
"integral timing nonlinearity"
- Nonlinearity comes from size (doping) of inverters and is stable over time  
→ can be calibrated
- Residual random jitter:  
<4 ps RMS exceeds best TDC

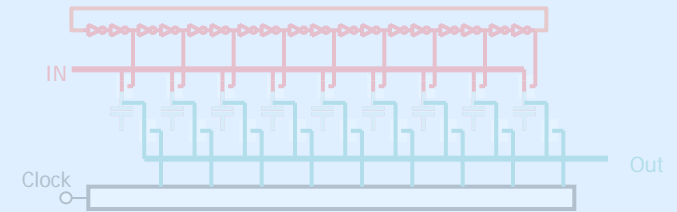


D. Stricker-Shaver, private communication

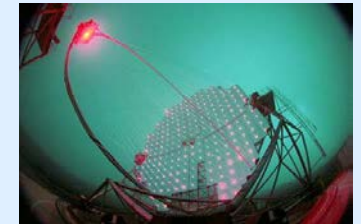
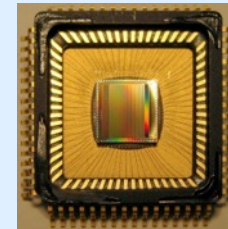


MEG @ PSI: 40 ps over 3000 channels

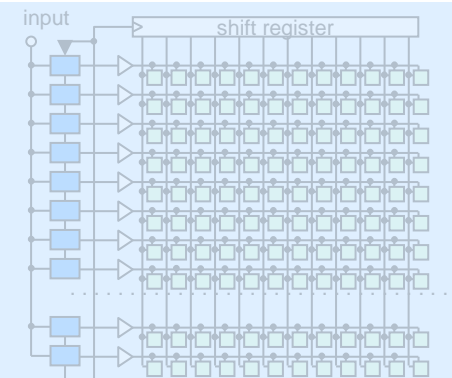
- Design Principles and Limitations



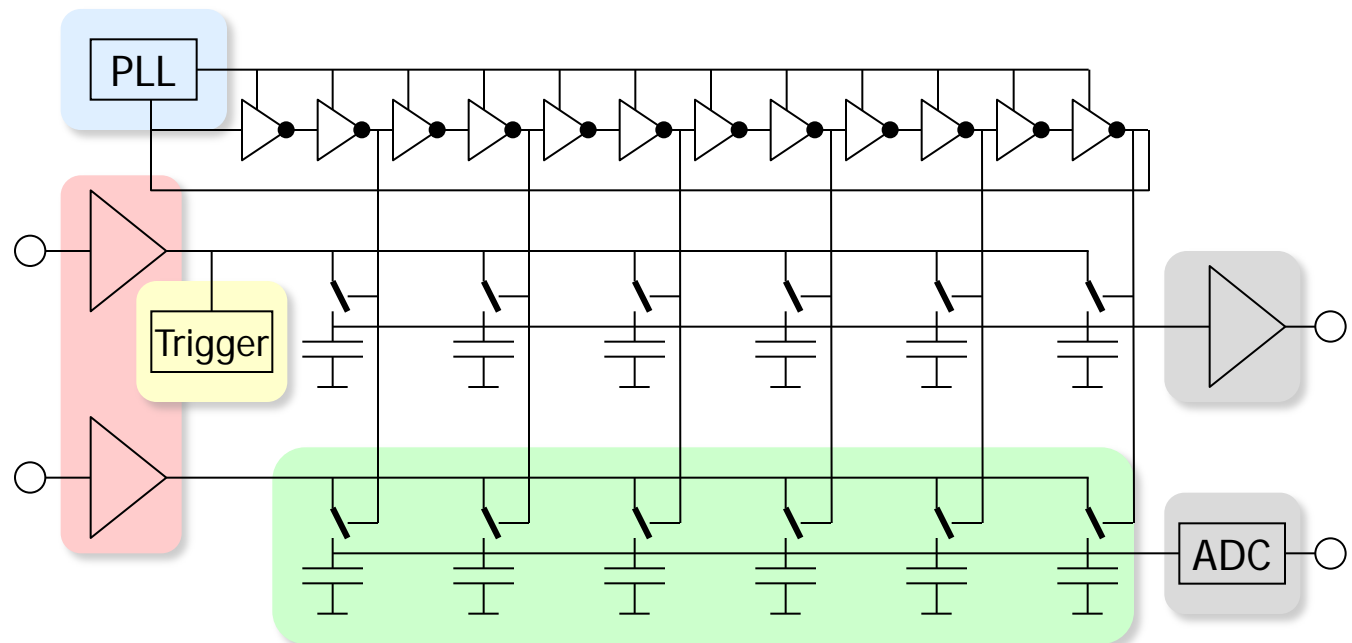
- Overview of Chips and Applications

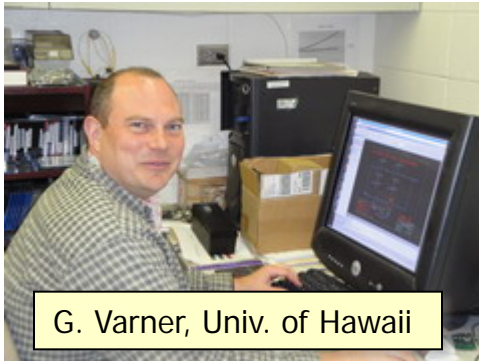


- Future Design Directions



- CMOS process (typically 0.35 ... 0.13  $\mu\text{m}$ )  $\rightarrow$  sampling speed
- Number of channels, sampling depth, differential input
- PLL for frequency stabilization
- Input buffer or passive input
- Analog output or (Wilkinson) ADC
- Internal trigger
- Exact design of sampling cell





G. Varner, Univ. of Hawaii



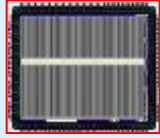
E. Delagnes  
D. Breton  
CEA Saclay



H. Frisch et al., Univ. Chicago



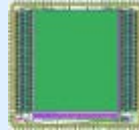
## STRAW3 LABRADOR3 TARGET



- 0.25  $\mu\text{m}$  TSMC
- Many chips for different projects (Belle, Anita, IceCube ...)

[www.phys.hawaii.edu/~idlab/](http://www.phys.hawaii.edu/~idlab/)

## AFTER SAM NECTARO



- 0.35  $\mu\text{m}$  AMS
- T2K TPC, Antares, Hess2, CTA

[matacq.free.fr](http://matacq.free.fr)



## PSEC1 - PSEC4

- 0.13  $\mu\text{m}$  IBM
- Large Area Picosecond Photo-Detectors Project (LAPPD)

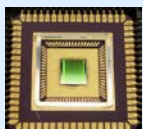
[psec.uchicago.edu](http://psec.uchicago.edu)

## DRS1



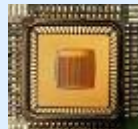
2002

## DRS2



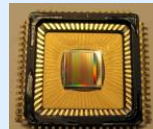
2004

## DRS3



2007

## DRS4



2008

- 0.25  $\mu\text{m}$  UMC
- Universal chip for many applications
- MEG experiment, MAGIC, Veritas, TOF-PET

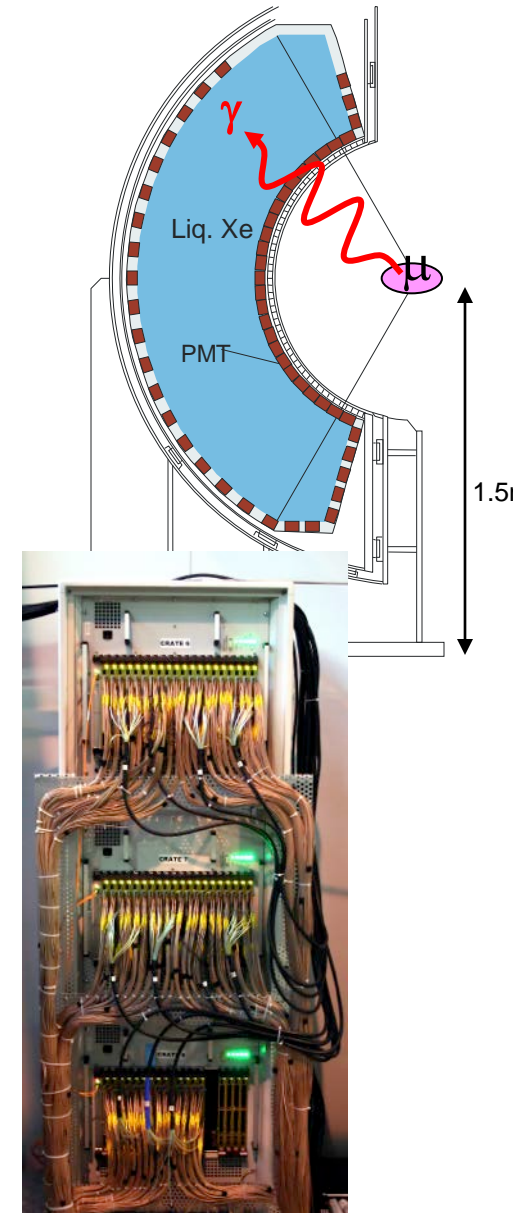
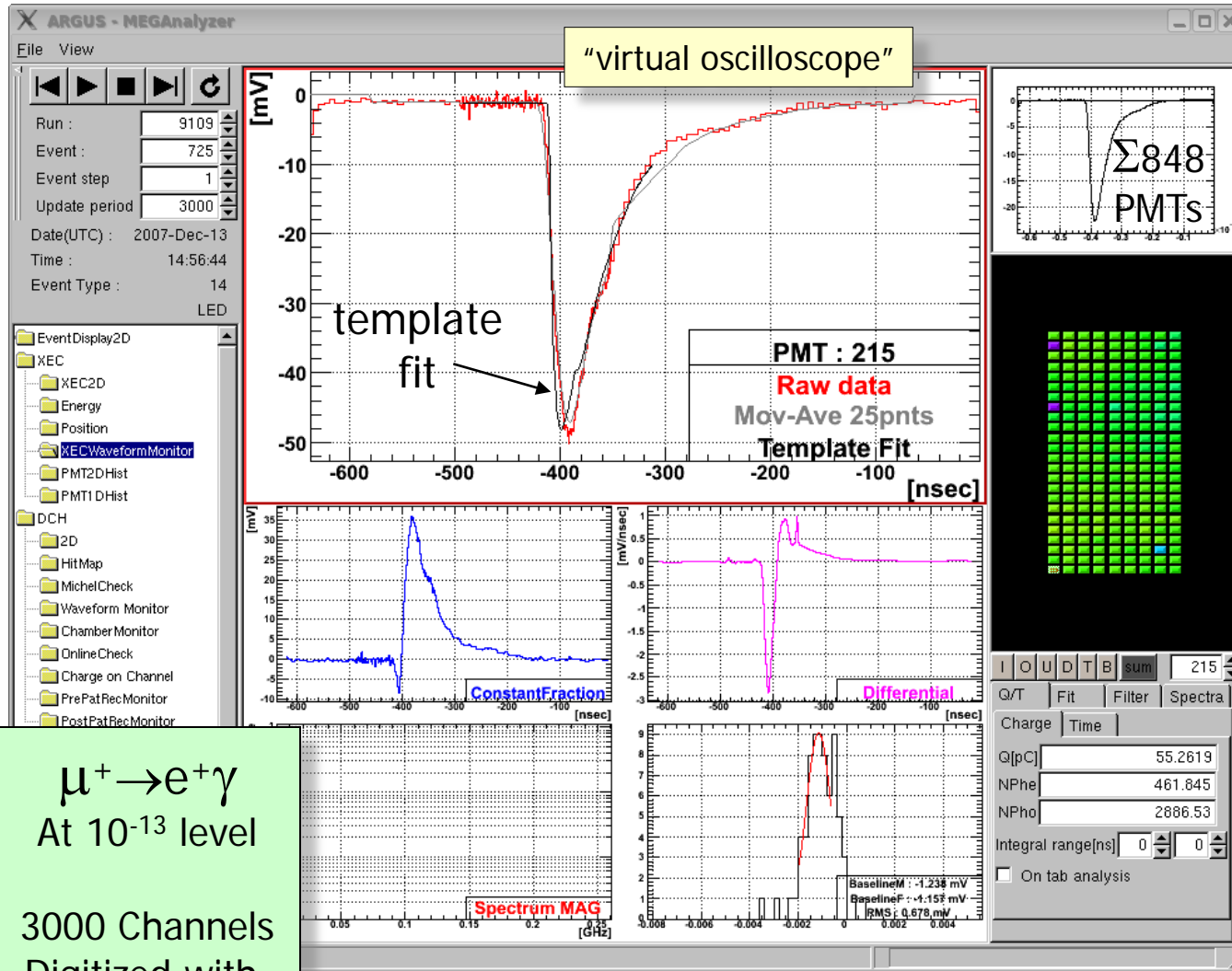


SR  
R. Dinapoli  
PSI, Switzerland

[drs.web.psi.ch](http://drs.web.psi.ch)



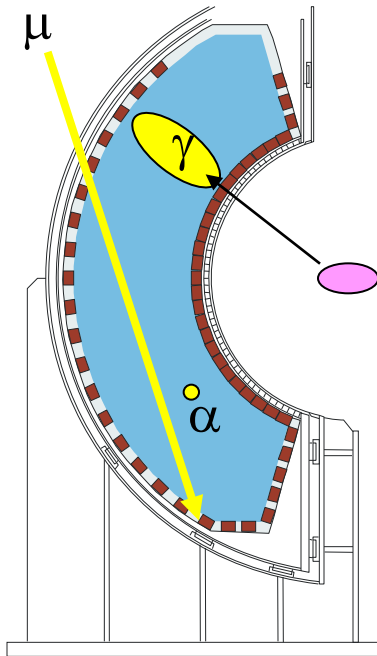
# MEG On-line waveform display



$\mu^+ \rightarrow e^+ \gamma$   
At  $10^{-13}$  level

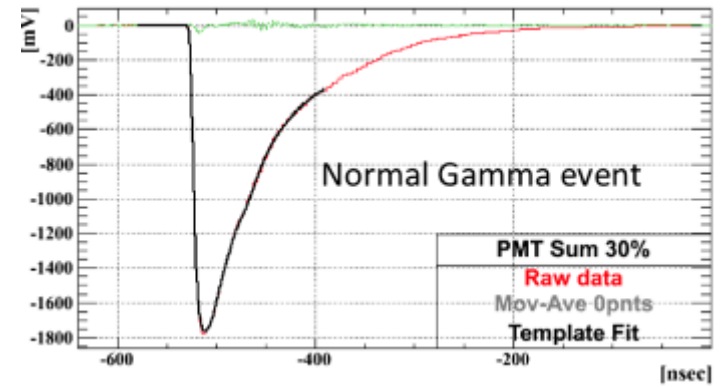
3000 Channels  
Digitized with  
**DRS4 chips** at  
1.6 GSPS

Drawback: 400 TB data/year

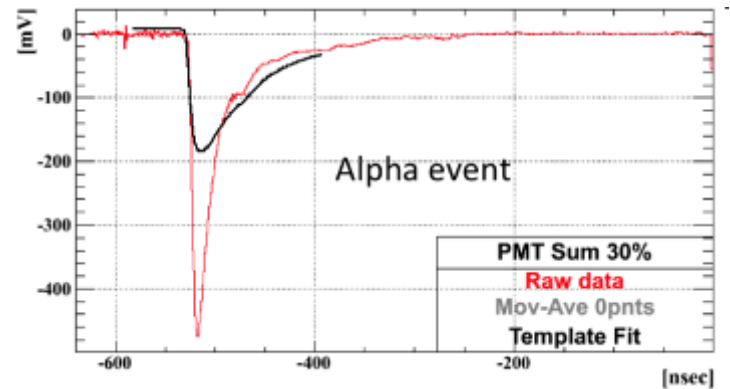


**Discovered  
offline !**

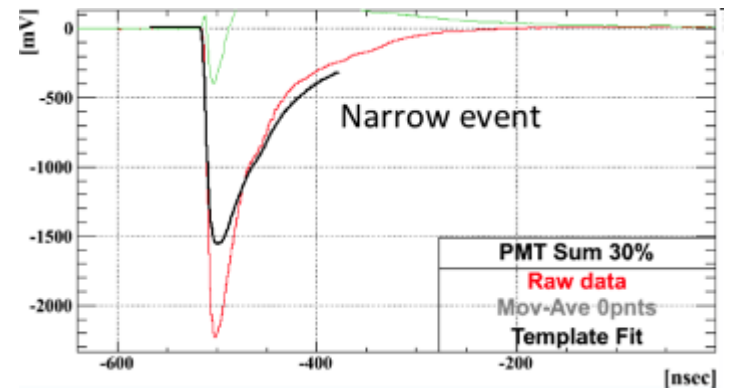
$\gamma$



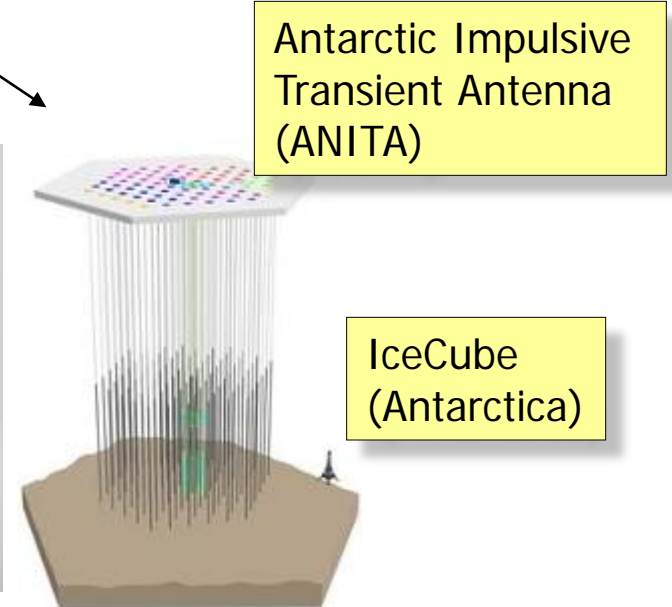
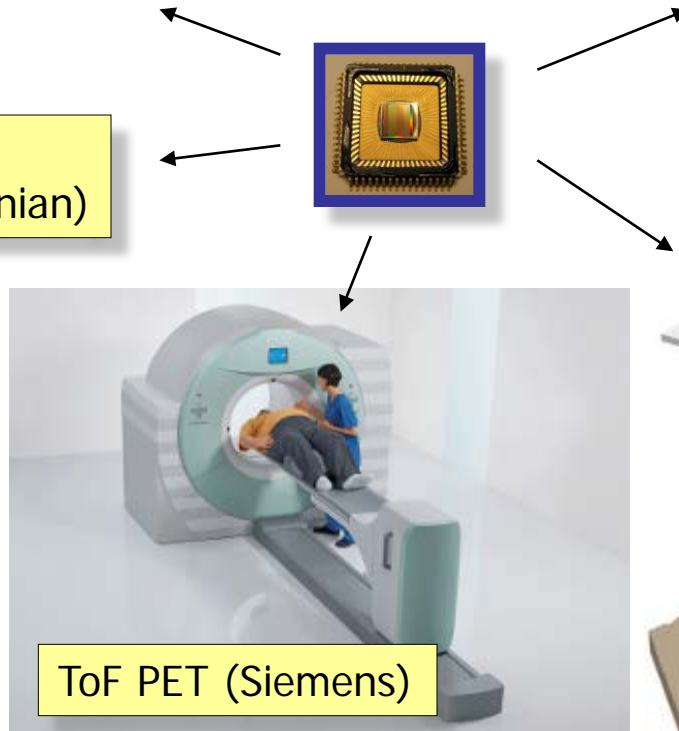
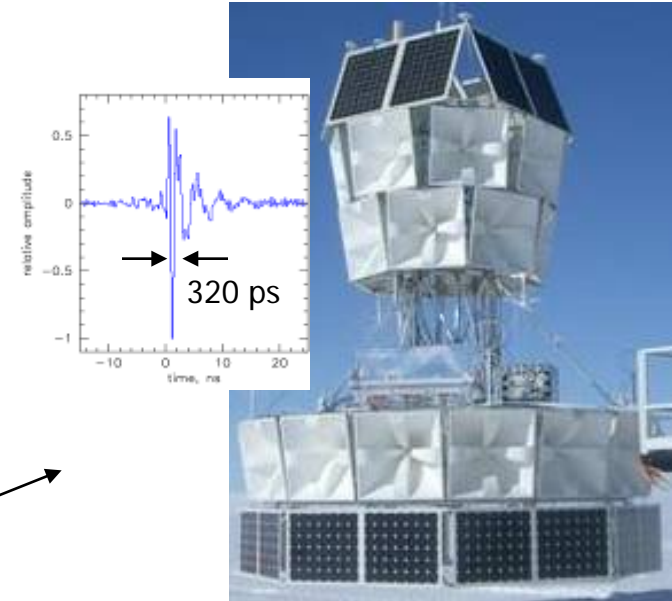
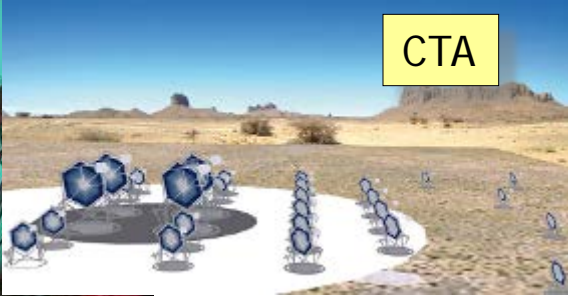
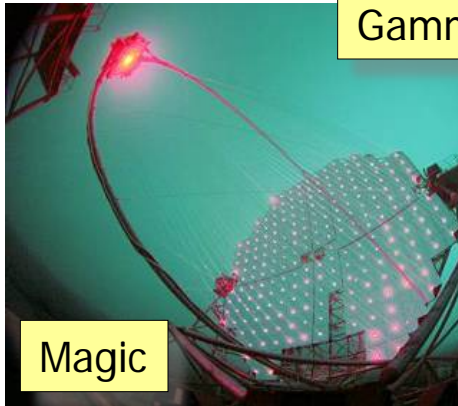
$\alpha$



$\mu$



# Other Applications

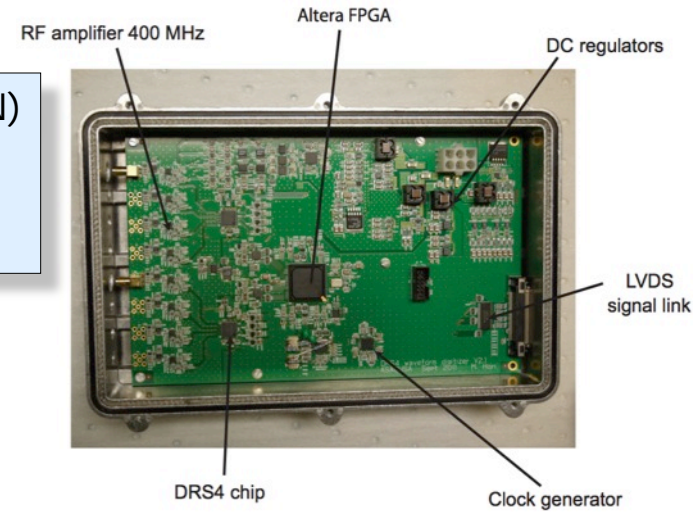


# Things you can buy and make

- DRS4 chip (PSI)
- 32+2 channels
- 12 bit 5 GSPS
- > 500 MHz analog BW
- 1024 sample points/chn.
- 110  $\mu$ s dead time



- M. Hori (CERN)
- DRS4 chip
- 8 channels
- LVDS links



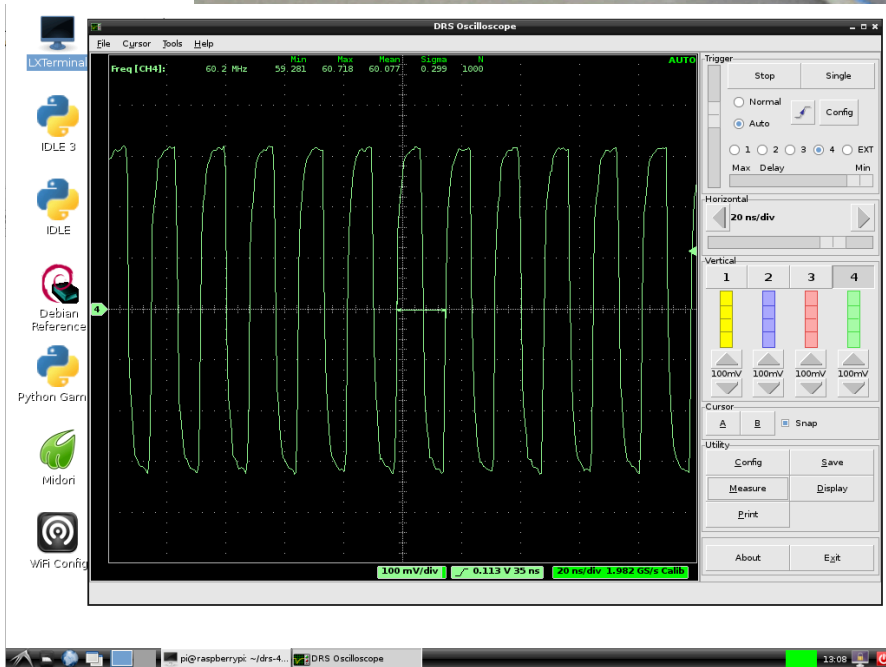
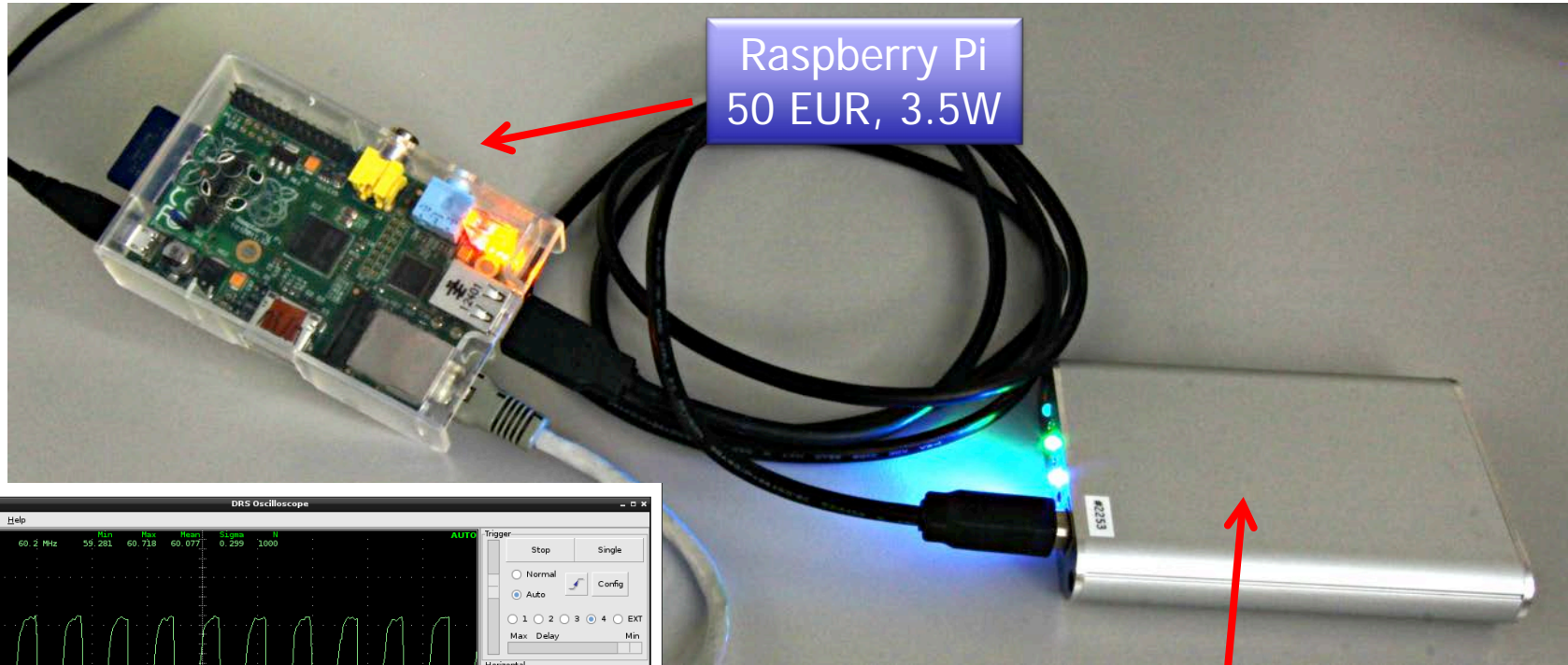
- DRS4 Evaluation Board
- 4 channels
- 12 bit 5 GSPS
- 750 MHz analog BW
- 1024 sample points/chn.
- 500 events/sec over USB 2.0



- SAM Chip (CEA/IN2PD)
- 2 channels
- 12 bit 3.2 GSPS
- 300 MHz analog BW
- 256 sample points/chn.
- On-board spectroscopy



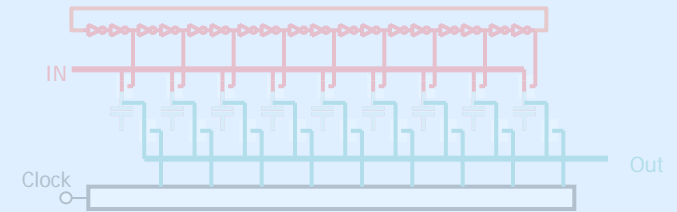
# The smallest DAQ system



DRS4 Evaluation Board  
900 EUR, 2.5W

Idea: Martin Brückner HU Berlin for HiSCORE

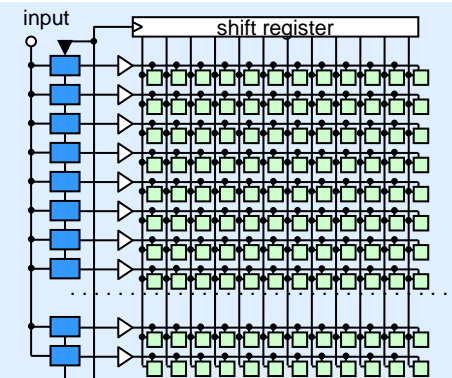
- Design Principles and Limitations

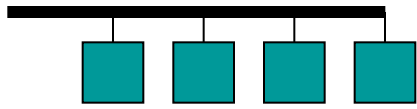


- Overview of Chips and Applications

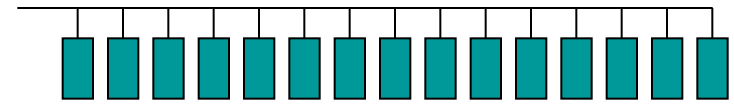
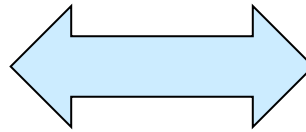


- Future Design Directions





Short sampling depth



Deep sampling depth

- Low parasitic input capacitance

How to combine best of both worlds?

- Wide input bus

- Low  $R_{on}$  write switches

→ High bandwidth

Digitize long waveforms

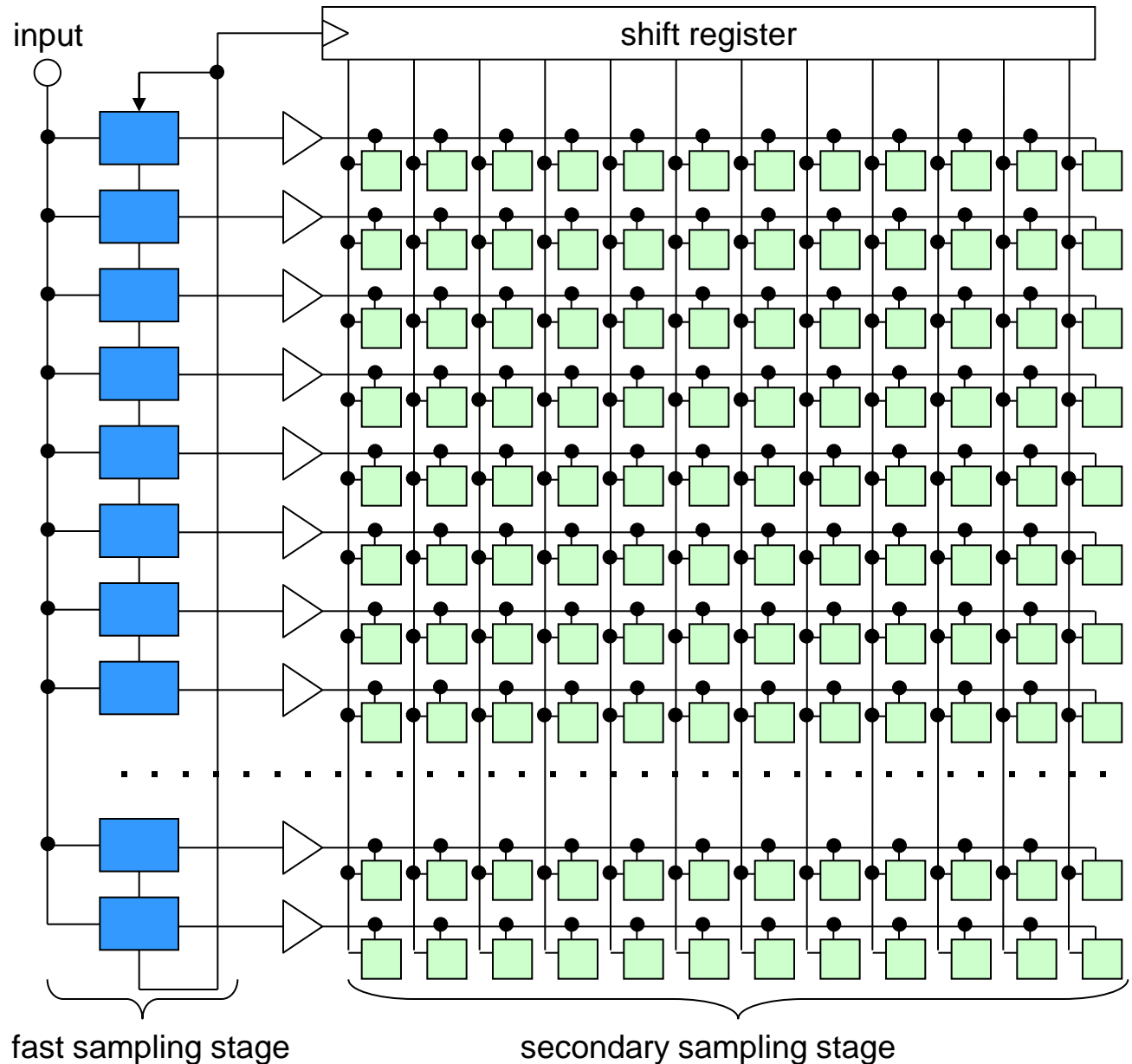
moderate long

trigger delay

- Faster sampling speed for a given trigger latency

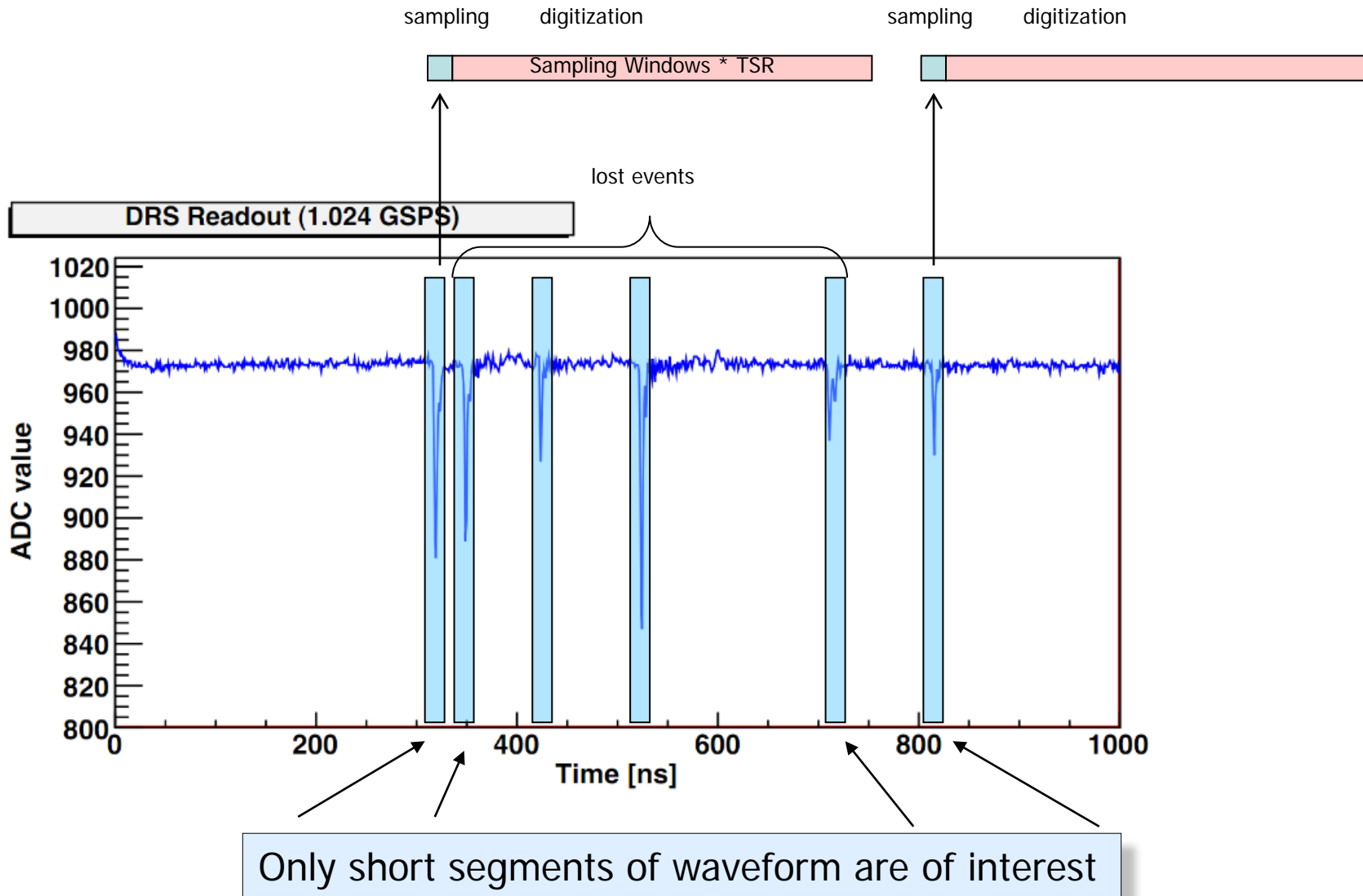
# Cascaded Switched Capacitor Arrays

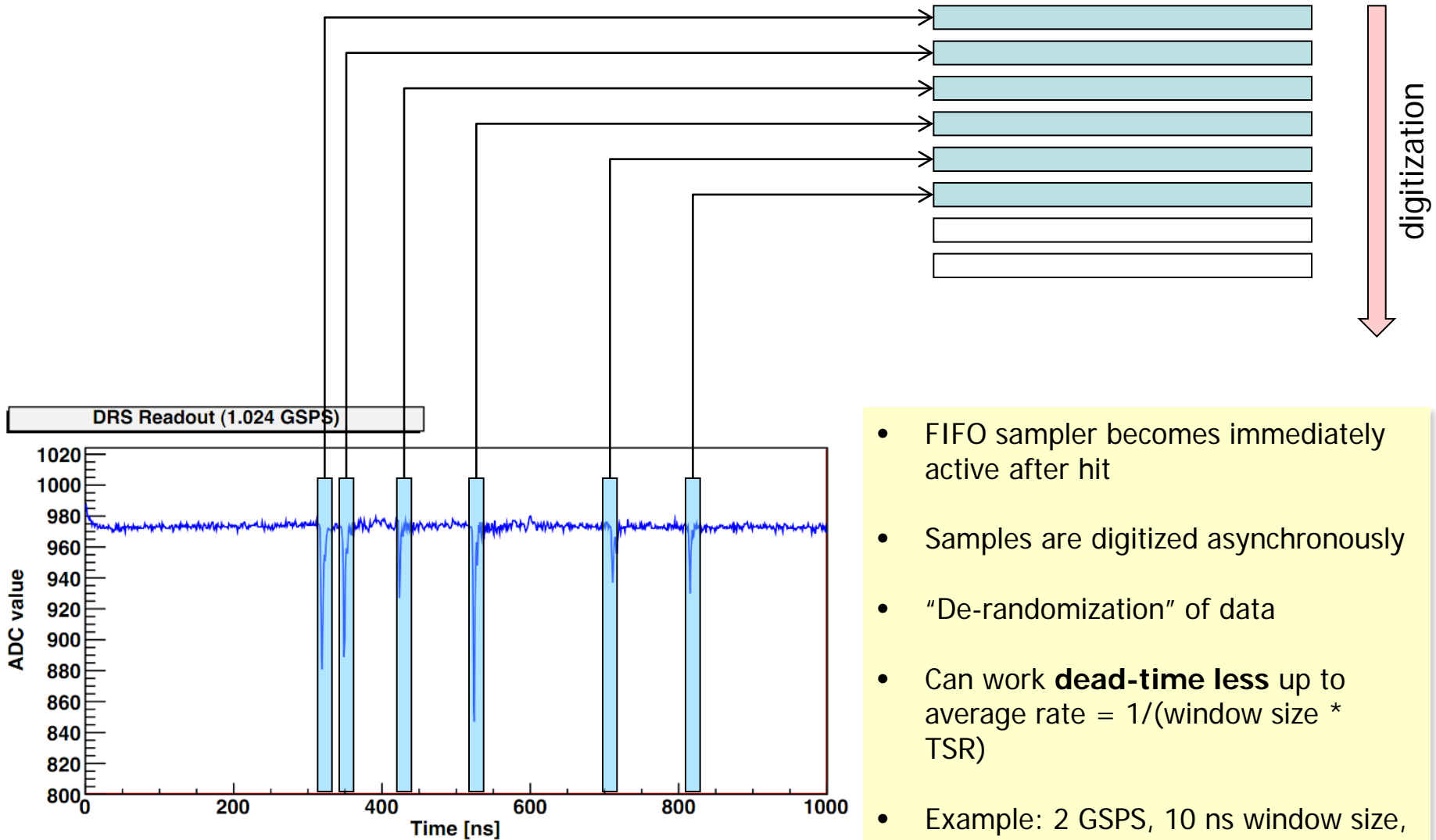
- 32 fast sampling cells (10 GSPS)  
→ small capacitance, high bandwidth
- 100 ps sample time, 3.1 ns hold time
- Hold time long enough to transfer voltage to secondary sampling stage with moderately fast buffer (300 MHz)
- Shift register gets clocked by inverter chain from fast sampling stage





# The dead-time problem





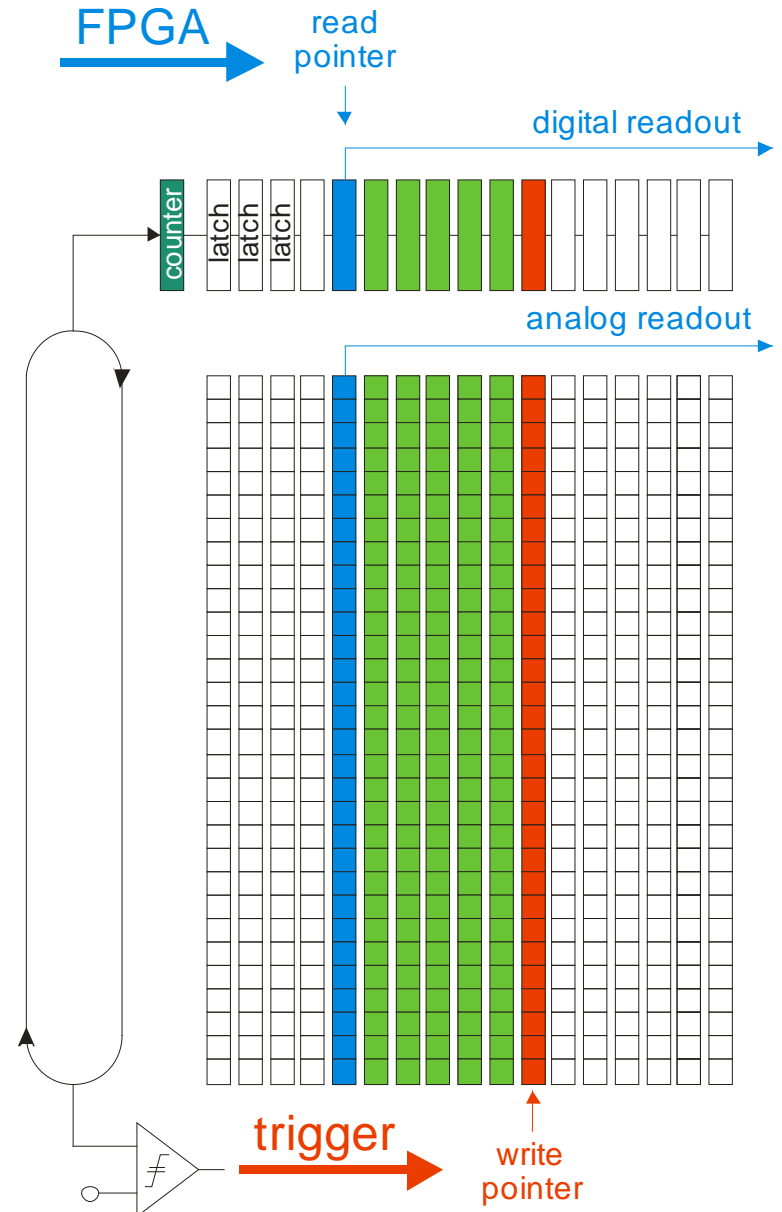
- FIFO sampler becomes immediately active after hit
- Samples are digitized asynchronously
- “De-randomization” of data
- Can work **dead-time less** up to average rate =  $1/(\text{window size} * \text{TSR})$
- Example: 2 GSPS, 10 ns window size, TSR = 60 → rate up to **1.6 MHz**

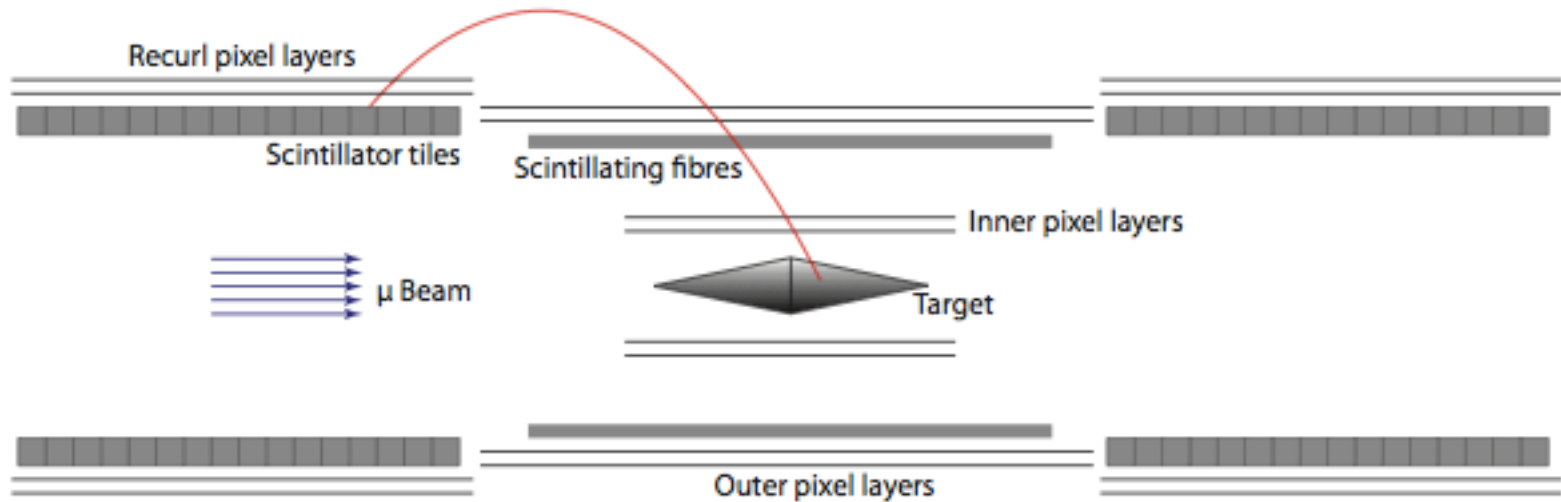
## DRS5 (PSI)

- Self-trigger writing of 128 short 32-bin segments (4096 bins total)
- Storage of 128 events
  - Accommodate long trigger latencies
  - Quasi dead time-free up to a few MHz,
  - Possibility to skip segments  
→ second level trigger
- Attractive replacement for CFG+TDC
- First version planned for 2014

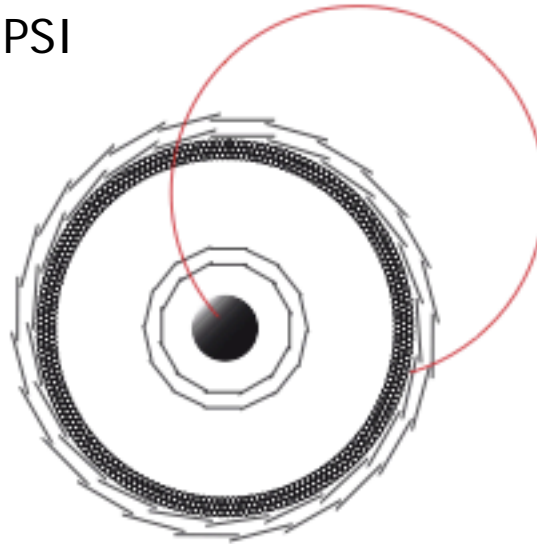
## CEA/Saclay

- Dual gain channels
- Dynamic power management (Read/Write parts)
- Region-of-interest readout





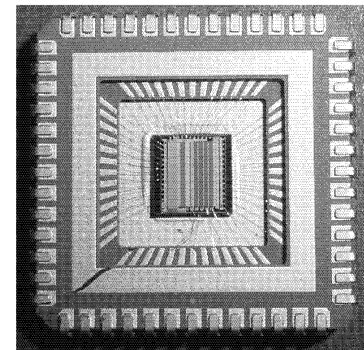
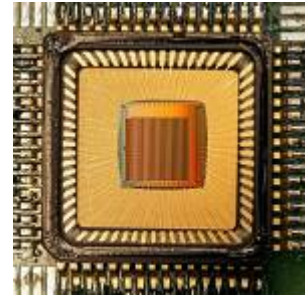
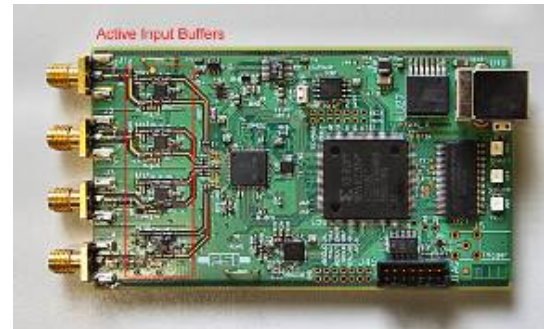
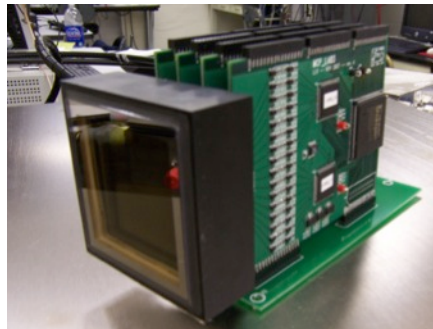
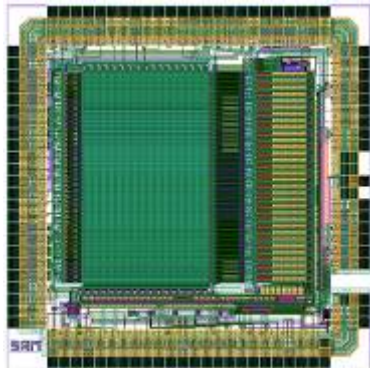
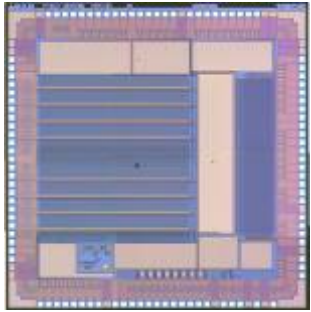
- Mu3e experiment planned at PSI with a sensitivity of  $10^{-16}$
- $2 \cdot 10^9$   $\mu$  stops/sec
- Scintillating fibres & tiles
  - 100ps timing resolution
  - 2-3 MHz hit rate
- Can only be done with DRS5!





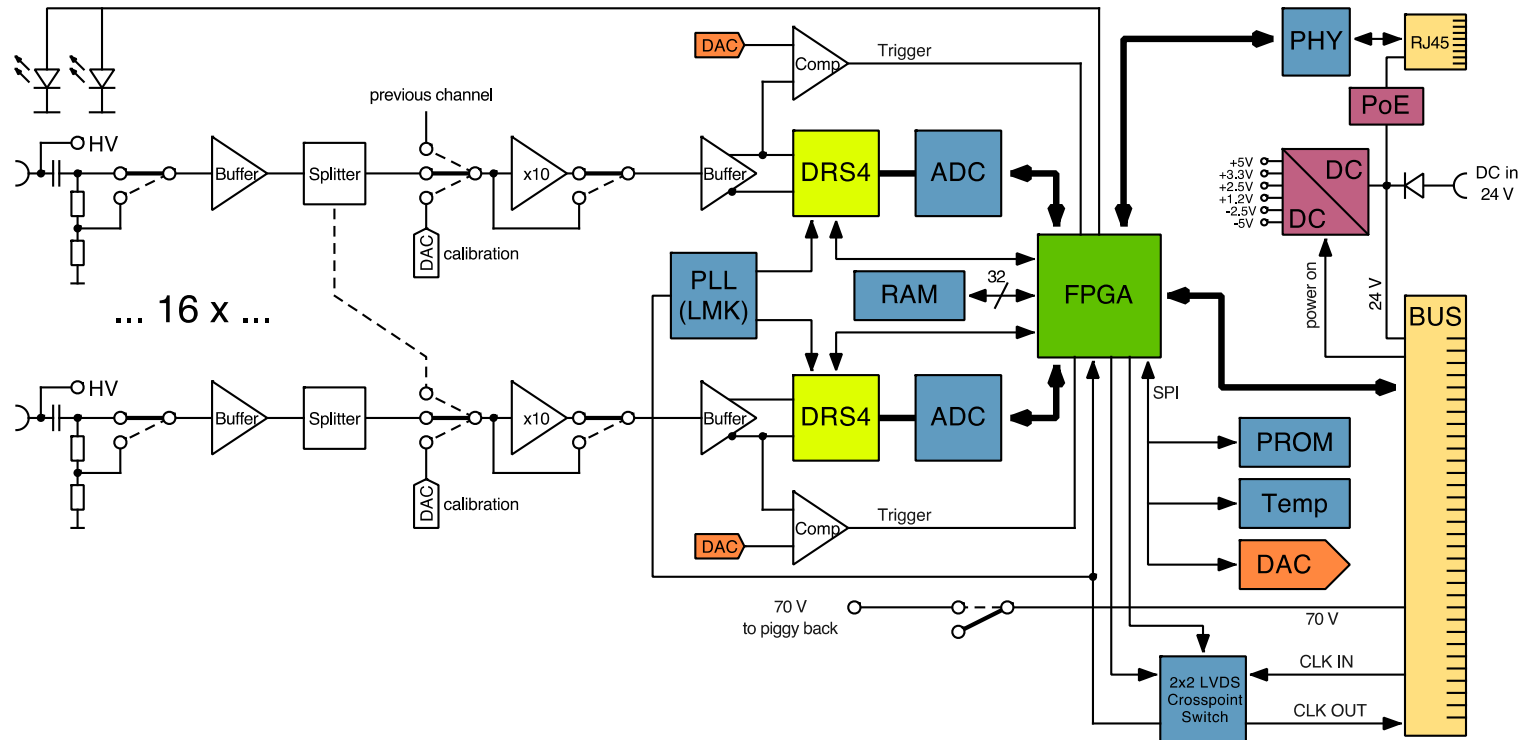
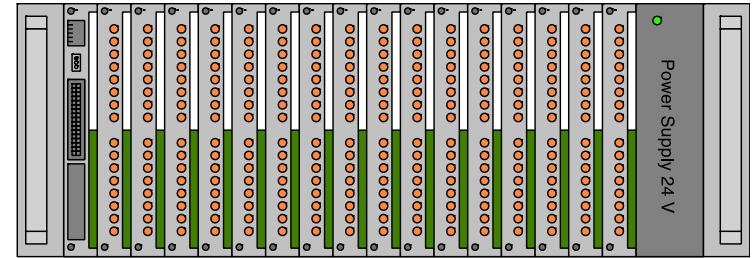
<http://drs.web.psi.ch>

- SCA technology offers tremendous opportunities
- Several chips and boards are on the market for evaluation
- New series of chips on the horizon might change front-end electronics significantly

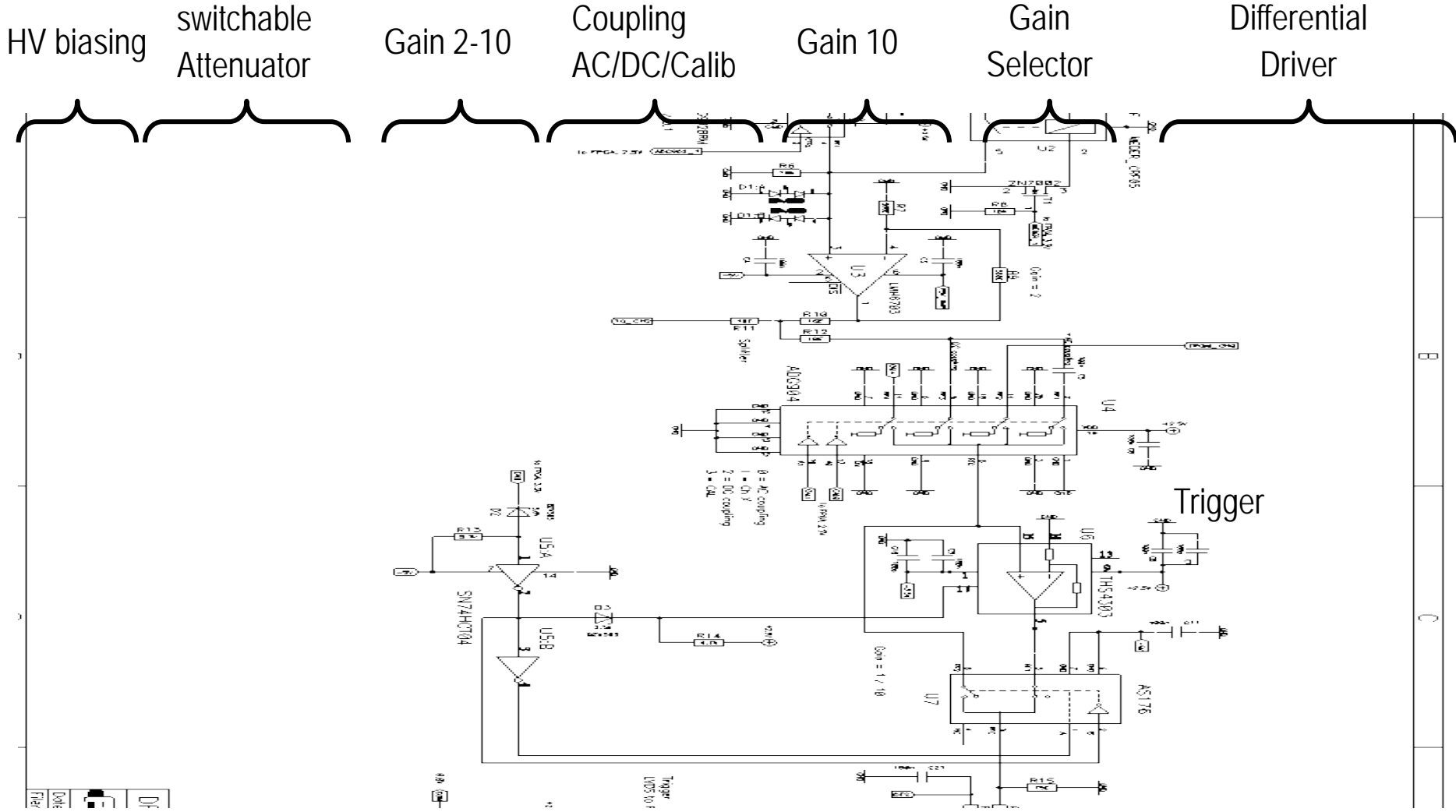




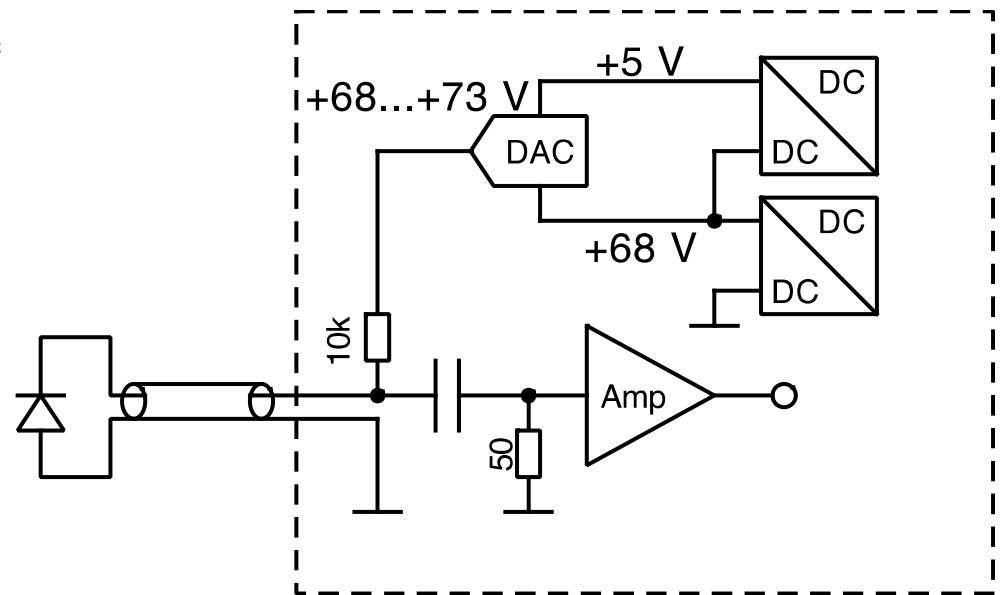
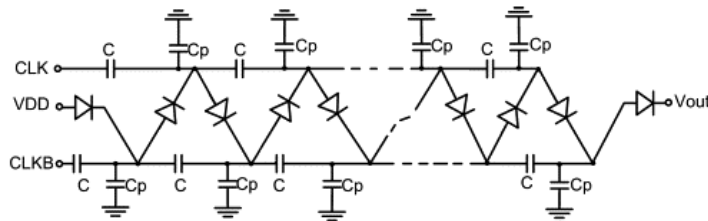
- 16 channels standalone (GBit Ethernet) or 3HE crate (256 channels)
- Variable gain 0.1/1/10 or 1/10/100
- Flexible integrated triggering
- Global clock synchronization
- Integrated SiPM biasing (up to 200V)
- Currently under development at PSI





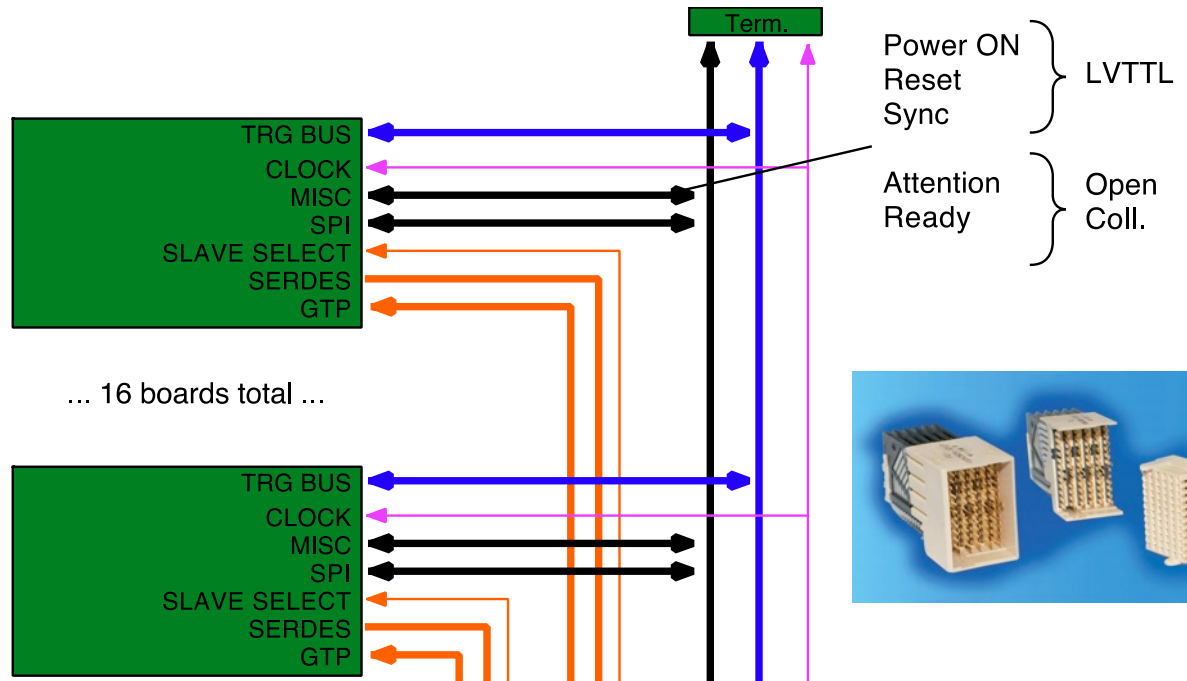


- Whole circuit works on virtual +68 V ground
- Connectors can stay on ground
- Regulation +68 V ... +73 V
- Current sense ~1 nA resolution
- ADC/DAC: ~8 EUR/channel
- Common DC-DC converter: +1 EUR / channel  
(Commercial or Cockcroft-Walton)

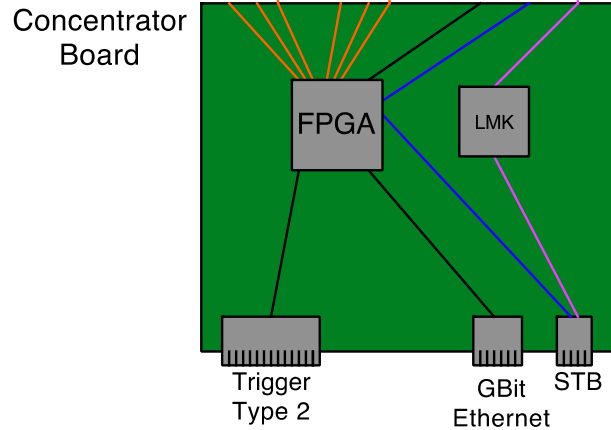
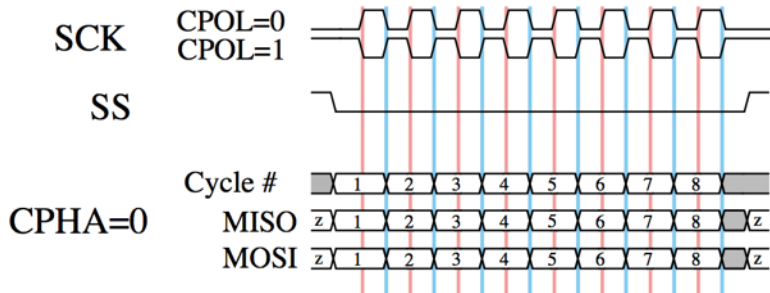
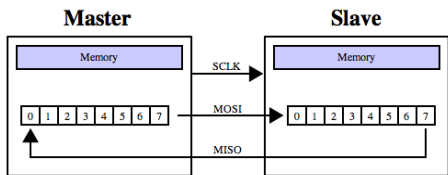


# Crate backplane & Clock distribution

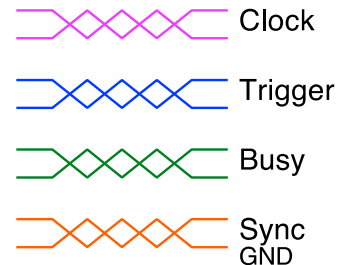
- Star connectivity for
  - GTP
  - SERDES
  - Slave Select
- Bus connectivity for
  - SPI (except SS)
  - MISC
  - Clock
  - Trigger

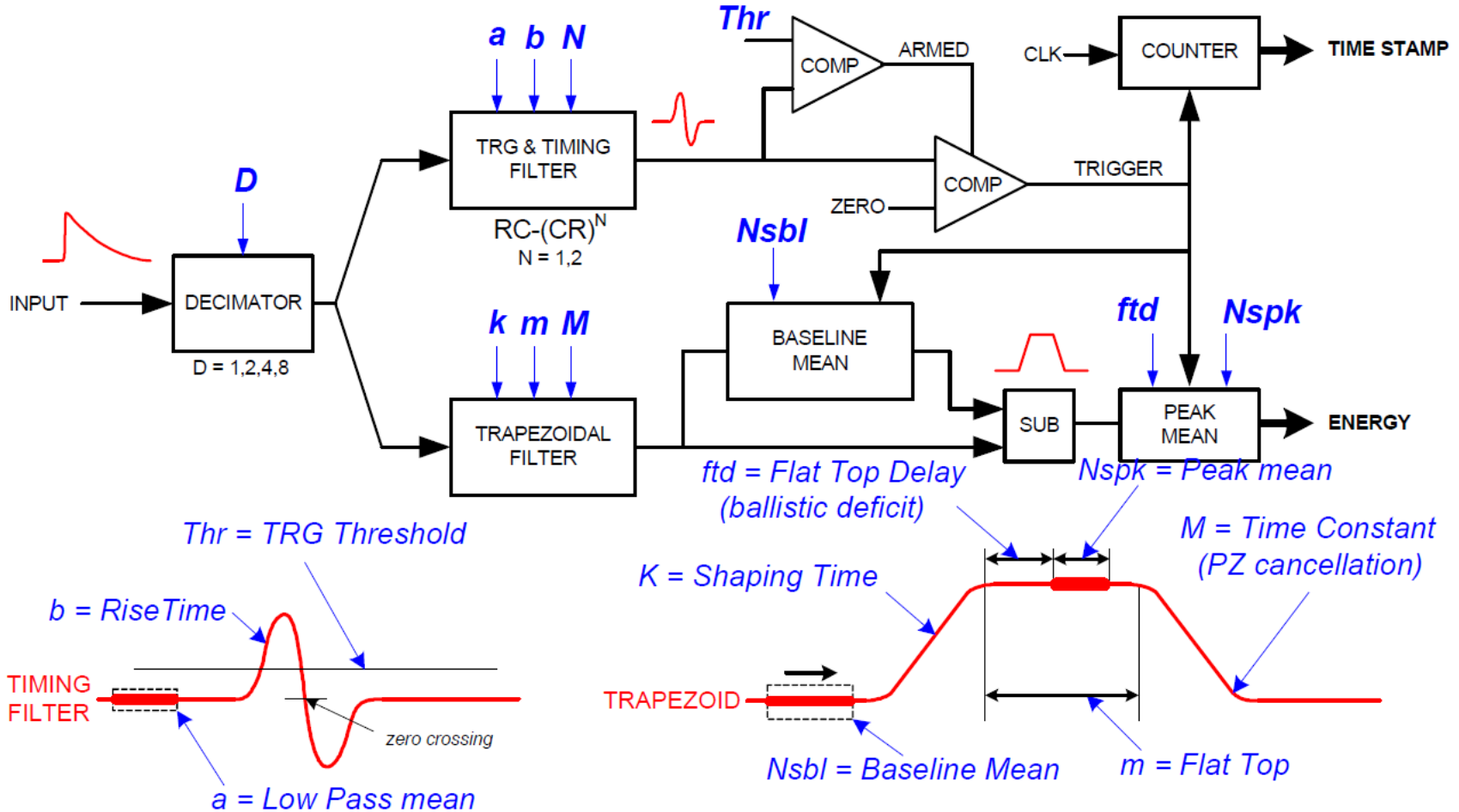


... 16 boards total ...



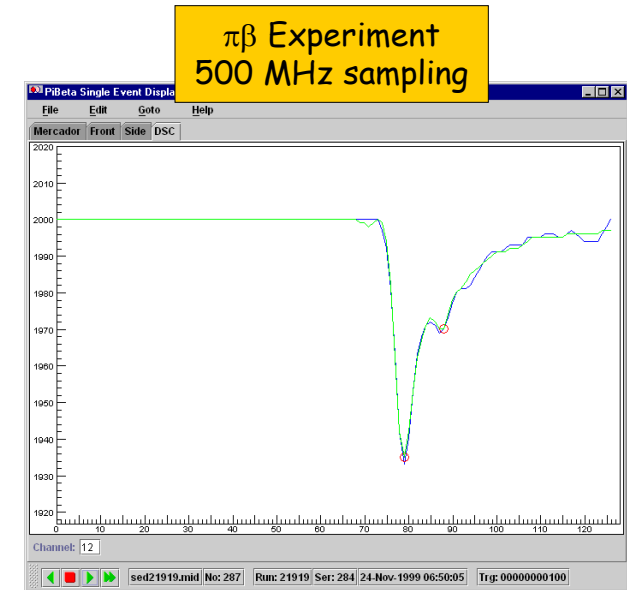
four differential pairs of RJ45 are used for Serial Trigger Bus



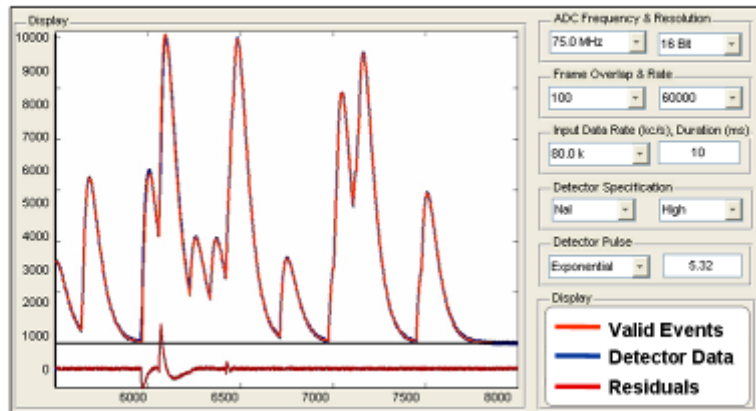


C. Tintori (CAEN)  
V. Jordanov *et al.*, NIM **A353**, 261 (1994)

- Determine “standard” PMT pulse by averaging over many events → “Template”
  - Find hit in waveform
  - Shift (“TDC”) and scale (“ADC”) template to hit
  - Minimize  $\chi^2$
  - Compare fit with waveform
  - Repeat if above threshold
- Store ADC & TDC values



- At 1,000 kc/s less than 10% of events cannot be decoded.



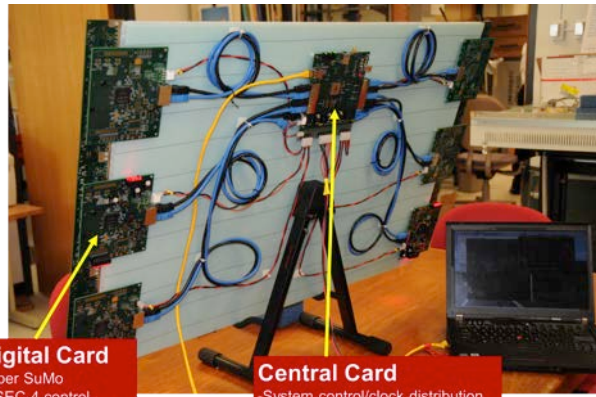
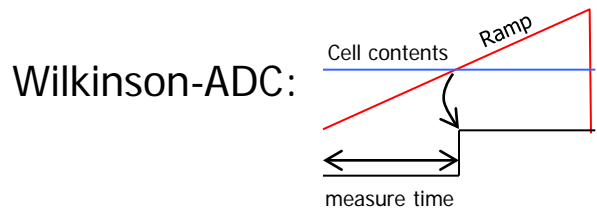
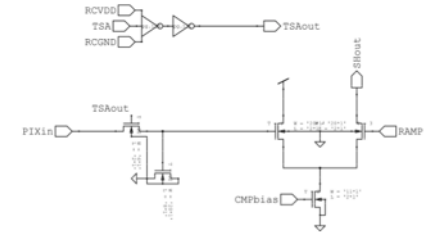
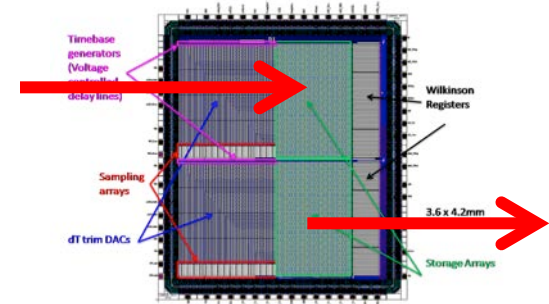
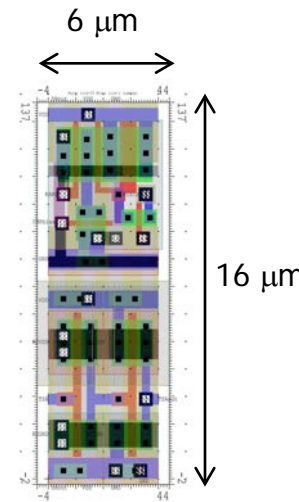
Southern Innovation

Implementation – Real Time.

14 bit  
60 MHz

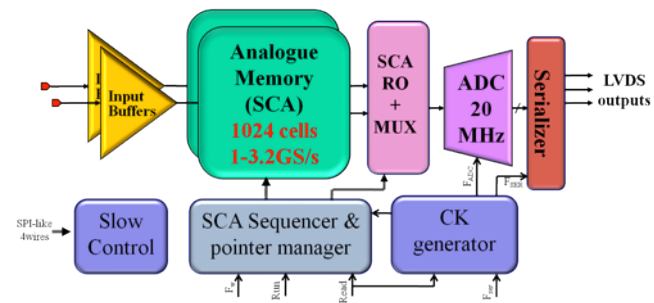
[www.southerninnovation.com](http://www.southerninnovation.com)

- LAB Chip Family (G. Varner)
  - Deep buffer (BLAB Chip: 64k)
  - Double buffer readout (LAB4)
  - Wilkinson ADC
- NECTAR0 Chip (E. Delagnes)
  - Matrix layout (short inverter chain)
  - Input buffer (300-400 MHz)
  - Large storage cell (>12 bit SNR)
  - 20 MHz pipeline ADC on chip
- PSEC4 Chip (E. Oberla, H. Grabas)
  - 15 GSPS
  - 1.6 GHz BW @ 256 cells
  - Wilkinson ADC



**Digital Card**  
-6 per SuMo  
-PSEC-4 control, trigger handling, local data reduction & calibration

**Central Card**  
-System control/clock distribution  
-Feature extraction & event pairing  
-CPU/GPU interface  
(gigabit Ethernet & USB 2.0)



# How to fix timing nonlinearity?

- LAB4 Chip (G. Varner) uses "Trim bits" to equalize inverter delays to  $< 10$  ps
- Dual-buffer readout for decreased dead time
- Wilkinson ADCs on chip

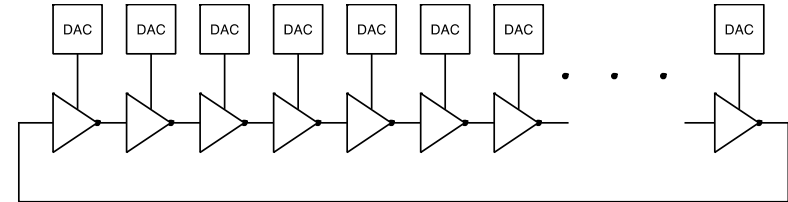
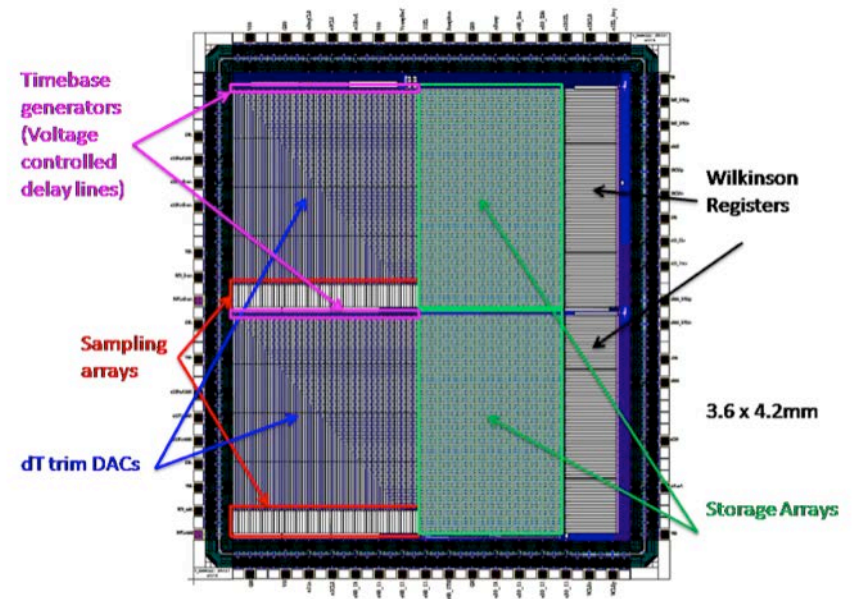


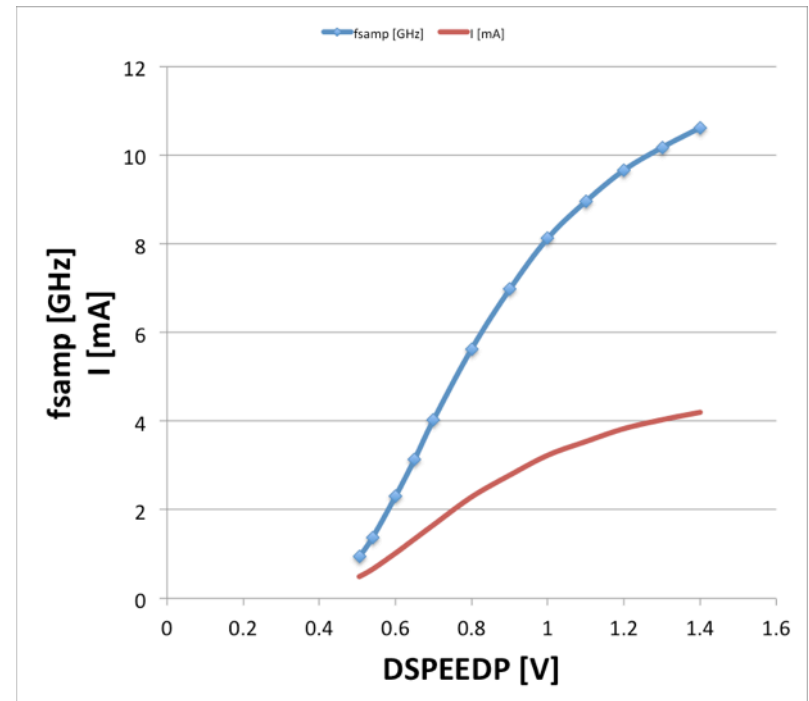
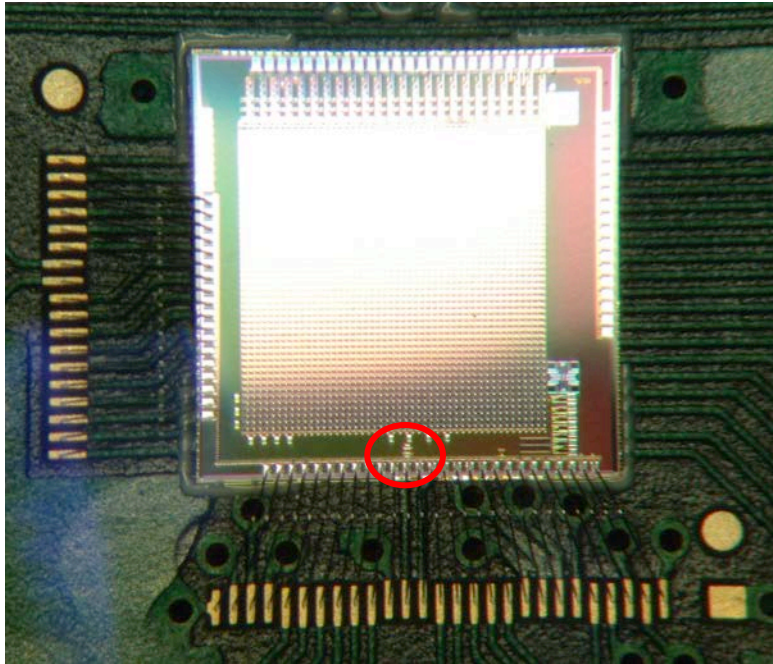
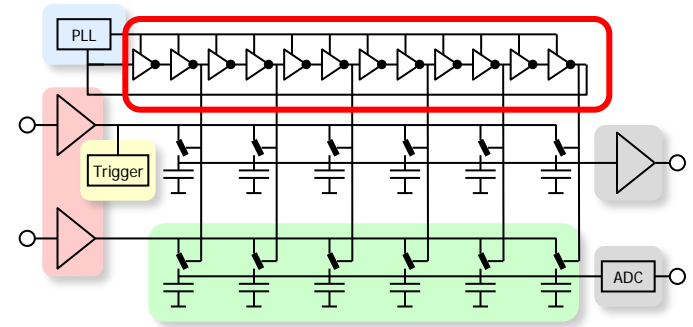
TABLE I  
PERFORMANCE SPECIFICATIONS FOR THE LAB4 ASIC.

Specification	Parameter
4096	samples/channel
1	channel/ASIC
$\leq 10$	ps residual timebase error
$\sim 10$	bits resolution (12-bits ADC)
256	samples convert window ( $\sim 64$ ns)
4	GSa/s sampling
$\leq 100$	$\mu$ s to read all samples
$\geq 1$ k	Hz sustained readout (multibuffer)



First tests will be reported on RT12 conference June 11-15, Berkeley, CA

- First silicon in 110 nm technology
- Implemented just inverter chain with 32 cells
- 4 mA @ 10 GSPS at 1.4 V





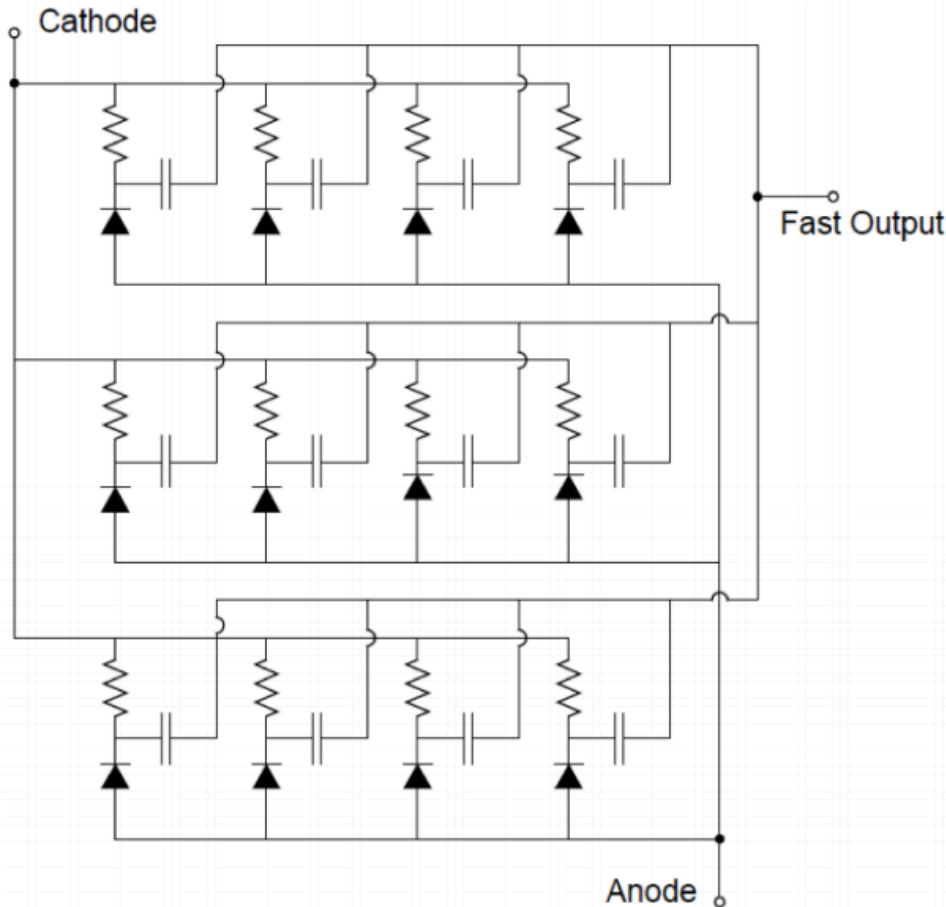


Figure 1, Schematic of the fast output structure

Rise-time < 100 ps possible

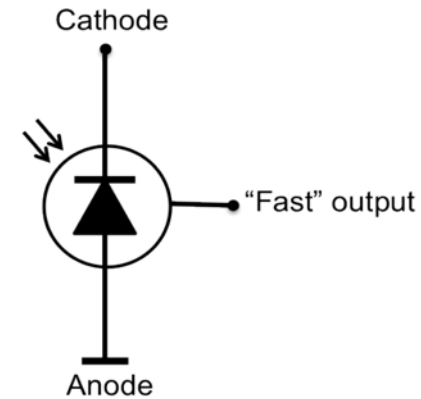


Figure 2, Configuration for fast mode

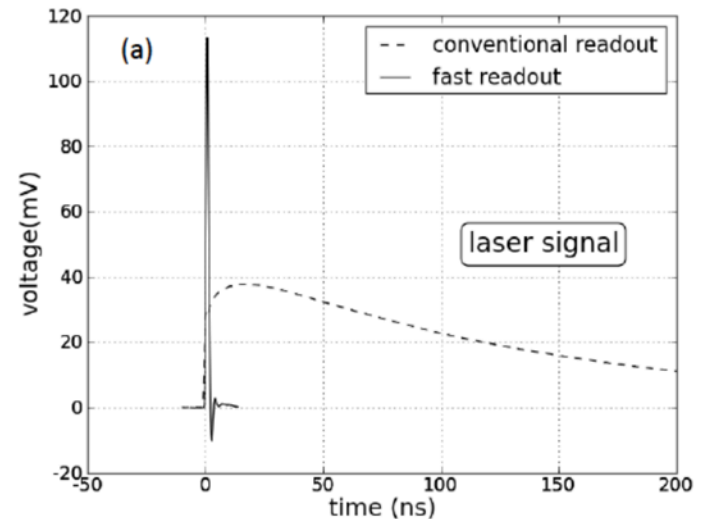
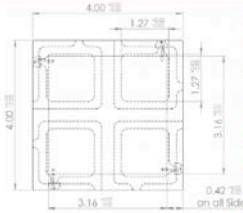
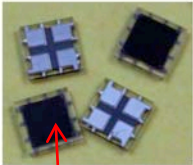


Figure 4, Signals from both modes when illuminated with a 50ps laser pulse.

## SensL 3mm pixel (Fast Mode) New 4 Side Tileable SMT Package

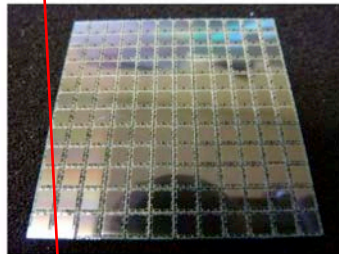


### ArrayFM-30035-SMT

- 4 Side tileable
- <math><500\mu\text{m}</math> from detector edge to package edge
- Clear molded top surface
- Low profile 0.6mm thickness
- Close coupling capable with 200 $\mu\text{m}$  from SPM to top of package
- Supply Options
  - Tape and Reel (3k/reel)
  - 49 unit tray for prototyping
- 3mm Available Now
  - 6mm sampling
  - 1mm in development

### 3mm SMT Application Example

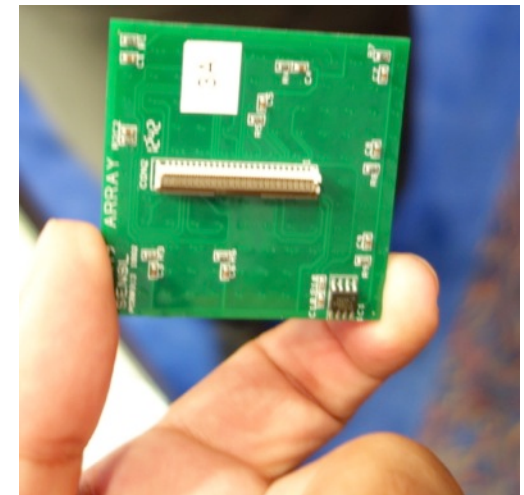
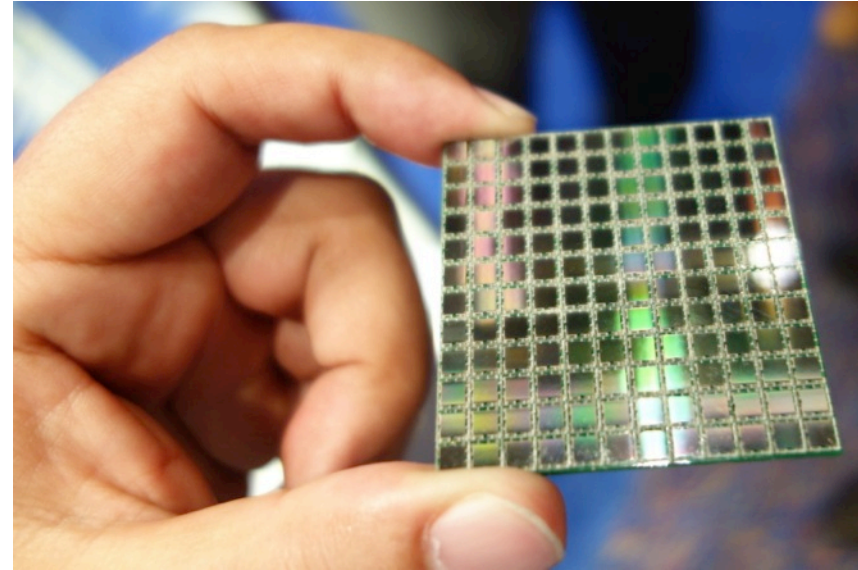
- 12x12 array of 3mm SMT
- 4.2mm pitch
- 200 $\mu\text{m}$  flatness on standard FR4 PCB



31st October, 2012

IEEE NSS/MIC Exhibitor Presentation

16



3x3 mm SiMP: 18 US\$ for >100pc (unverified)

## DRS4

### FEATURES

- Single 2.5 V power supply
- Sampling speed 700 MSPS to 5 GSPS
- 8+1 channels with 1024 storage cells each
- Cascading of channels or chips allows deeper sampling depth
- Differential inputs with 950 MHz bandwidth
- Differential outputs for direct ADC interfacing
- Transparent mode for integrated triggering
- Readout time: 30 ns \* number of samples
- Simultaneous reading and writing
- Multiplexed or parallel analog outputs
- Low power: 140 mW typical at 2 GSPS (17.5 mW per channel)
- Low integral nonlinearity:  $0.5 \times 10^{-3}$  at 1 V range
- High SNR: 69 dB after offset correction
- Low Noise: 0.35 mV after offset correction

### APPLICATIONS

- Instrumentation and Measurement
- Photomultiplier, Drift Chamber and APD Readout
- Low Cost Digital Oscilloscopes
- Ultrasound Equipment

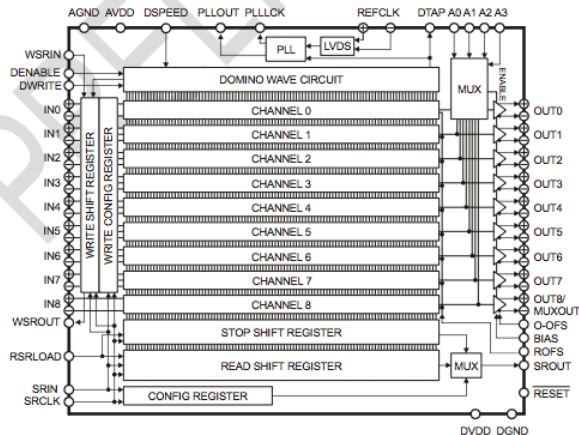
### GENERAL DESCRIPTION

The Domino Ring Sampler (DRS) is a switched capacitor array (SCA) capable of sampling 9 differential input channels at a sampling speed of 700 MSPS to 5 GSPS (6 GSPS for selected chips). The analog waveform is stored in 1024 sampling cells per channel, and can be read out after sampling via a shift register clocked at 33 MHz for external digitization.

The write signal for the sampling cells is generated by a chain of inverters (domino principle) generated on the chip and stabilized by a PLL. The domino wave is running continuously until stopped by a trigger. A read shift register clocks the contents of the sampling cells either to a multiplexed or to individual outputs, where it can be digitized with an external ADC. It is possible to read out only a part of the waveform to reduce the digitization time.

The high channel density, high analog bandwidth of 950 MHz, and low noise of 0.35 mV (after offset calibration) makes this chip ideally suited for low power, high speed, high precision waveform digitizing. Fabricated on an advanced CMOS process in a radiation hard design, the DRS4 is available in a 76-pin quad flat non-leaded package (QFN).

### FUNCTIONAL BLOCK DIAGRAM



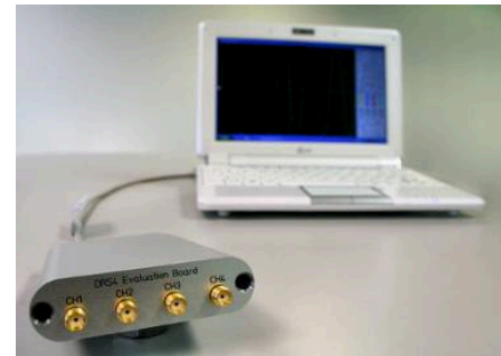
REV. 0.9

Please check for updates at <http://drs.web.psi.ch/datasheets>

S. Ritt, Paul Scherrer Institute, CH-5232 Villigen PSI, Switzerland, Tel.: +41 56 310 3728, [stefan.ritt@psi.ch](mailto:stefan.ritt@psi.ch)

# DRS4 Evaluation Board User's Manual

Board Revision 4.0  
as of February 2012  
Last revised: November 22, 2012



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Please check for possible updates of this manual under <http://drs.web.psi.ch/datasheets>